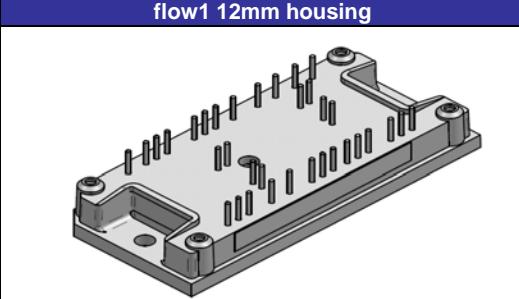
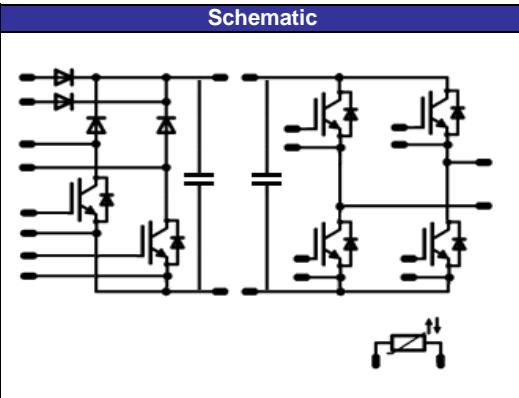


flowSOL 1 BI	600V/50A
<p><b>Features</b></p> <ul style="list-style-type: none"> <li>• Low inductive 12mm flow1 package</li> <li>• Booster: <ul style="list-style-type: none"> <li>◦ Dual boost topology</li> <li>◦ High-speed IGBT + ultrafast FWD</li> <li>◦ Bypass rectifier</li> </ul> </li> <li>• Inverter: <ul style="list-style-type: none"> <li>◦ H-bridge topology</li> <li>◦ High-speed IGBT + ultrafast FWD</li> </ul> </li> <li>• Integrated DC-capacitors</li> <li>• Temperature sensor</li> </ul>	
<p><b>Target Applications</b></p> <ul style="list-style-type: none"> <li>• Solar Inverter: Transformer-less solar inverter with bipolar modulation with high efficiency/cost ratio Primary of a transformer based solar inverter with resonant switching</li> </ul>	
<p><b>Types</b></p> <ul style="list-style-type: none"> <li>• 10-FY06BIA050SG-M523E18</li> </ul>	

## Maximum Ratings

T<sub>j</sub>=25°C, unless otherwise specified

Parameter	Symbol	Condition	Value	Unit
<b>Bypass Diode</b>				
Repetitive peak reverse voltage	V <sub>RRM</sub>		1600	V
Forward current per diode	I <sub>FAV</sub>	DC current T <sub>h</sub> =80°C T <sub>c</sub> =80°C	39 53	A
Surge forward current	I <sub>FSM</sub>		370	A
I <sup>2</sup> t-value	I <sup>2</sup> t	t <sub>p</sub> =10ms T <sub>j</sub> =25°C	370	A <sup>2</sup> s
Power dissipation per Diode	P <sub>tot</sub>	T <sub>j</sub> =T <sub>j</sub> max T <sub>h</sub> =80°C T <sub>c</sub> =80°C	46 69	W
Maximum Junction Temperature	T <sub>j</sub> max		150	°C

## Input Boost IGBT

Collector-emitter break down voltage	V <sub>CE</sub>		600	V
DC collector current	I <sub>C</sub>	T <sub>j</sub> =T <sub>j</sub> max T <sub>h</sub> =80°C T <sub>c</sub> =80°C	39 52	A
Repetitive peak collector current	I <sub>Cpulse</sub>	t <sub>p</sub> limited by T <sub>j</sub> max	150	A
Power dissipation per IGBT	P <sub>tot</sub>	T <sub>j</sub> =T <sub>j</sub> max T <sub>h</sub> =80°C T <sub>c</sub> =80°C	83 126	W
Gate-emitter peak voltage	V <sub>GE</sub>		±20	V
Short circuit ratings	t <sub>sc</sub> V <sub>CC</sub>	T <sub>j</sub> ≤150°C V <sub>GE</sub> =15V	5 400	μs V
Maximum Junction Temperature	T <sub>j</sub> max		175	°C

## Maximum Ratings

T<sub>j</sub>=25°C, unless otherwise specified

Parameter	Symbol	Condition	Value	Unit
<b>Input Boost Inverse Diode</b>				
Peak Repetitive Reverse Voltage	V <sub>RRM</sub>	T <sub>j</sub> =25°C	600	V
DC forward current	I <sub>F</sub>	T <sub>j</sub> =T <sub>j</sub> max T <sub>h</sub> =80°C T <sub>c</sub> =80°C	19 25	A
Repetitive peak forward current	I <sub>FRM</sub>	t <sub>p</sub> limited by T <sub>j</sub> max	20	A
Power dissipation per Diode	P <sub>tot</sub>	T <sub>j</sub> =T <sub>j</sub> max T <sub>h</sub> =80°C T <sub>c</sub> =80°C	39 47	W
Maximum Junction Temperature	T <sub>j</sub> max		150	°C
<b>Input Boost Diode</b>				
Peak Repetitive Reverse Voltage	V <sub>RRM</sub>	T <sub>j</sub> =25°C	600	V
DC forward current	I <sub>F</sub>	T <sub>j</sub> =T <sub>j</sub> max T <sub>h</sub> =80°C T <sub>c</sub> =80°C	23 27	A
Repetitive peak forward current	I <sub>FRM</sub>	t <sub>p</sub> limited by T <sub>j</sub> max	120	A
Power dissipation	P <sub>tot</sub>	T <sub>j</sub> =T <sub>j</sub> max T <sub>h</sub> =80°C T <sub>c</sub> =80°C	40 60	W
Maximum Junction Temperature	T <sub>j</sub> max		150	°C
<b>H-Bridge IGBT</b>				
Collector-emitter break down voltage	V <sub>CE</sub>	T <sub>j</sub> =25°C	600	V
DC collector current	I <sub>C</sub>	T <sub>j</sub> =T <sub>j</sub> max T <sub>h</sub> =80°C T <sub>c</sub> =80°C	39 52	A
Repetitive peak collector current	I <sub>Cpulse</sub>	t <sub>p</sub> limited by T <sub>j</sub> max	150	A
Power dissipation per IGBT	P <sub>tot</sub>	T <sub>j</sub> =T <sub>j</sub> max T <sub>h</sub> =80°C T <sub>c</sub> =80°C	83 126	W
Gate-emitter peak voltage	V <sub>GE</sub>		±20	V
Short circuit ratings	t <sub>SC</sub> V <sub>CC</sub>	T <sub>j</sub> ≤150°C V <sub>GE</sub> =15V	5 400	μs V
Maximum Junction Temperature	T <sub>j</sub> max		175	°C
<b>H-Bridge Diode</b>				
Peak Repetitive Reverse Voltage	V <sub>RRM</sub>	T <sub>j</sub> =25°C	600	V
DC forward current	I <sub>F</sub>	T <sub>j</sub> =T <sub>j</sub> max T <sub>h</sub> =80°C T <sub>c</sub> =80°C	23 31	A
Repetitive peak forward current	I <sub>FRM</sub>	t <sub>p</sub> limited by T <sub>j</sub> max	120	A
Power dissipation per Diode	P <sub>tot</sub>	T <sub>j</sub> =T <sub>j</sub> max T <sub>h</sub> =80°C T <sub>c</sub> =80°C	40 60	W
Maximum Junction Temperature	T <sub>j</sub> max		150	°C
<b>DC link Capacitor</b>				
Max.DC voltage	V <sub>MAX</sub>	T <sub>c</sub> =25°C	630	V

## Maximum Ratings

T<sub>j</sub>=25°C, unless otherwise specified

Parameter	Symbol	Condition	Value	Unit
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### Thermal Properties

Storage temperature	T <sub>stg</sub>		-40...+125	°C
Operation temperature under switching condition	T <sub>op</sub>		-40...+(T <sub>jmax</sub> - 25)	°C

### Insulation Properties

Insulation voltage	V <sub>is</sub>	t=2s	DC voltage	4000	V
Creepage distance				min 12,7	mm
Clearance				min 12,7	mm

### Characteristic Values

Parameter	Symbol	Conditions				Value			Unit
		V <sub>GE</sub> [V] or V <sub>GS</sub> [V]	V <sub>I</sub> [V] or V <sub>CE</sub> [V] or V <sub>DS</sub> [V]	I <sub>C</sub> [A] or I <sub>F</sub> [A] or I <sub>D</sub> [A]	T <sub>J</sub>	Min	Typ	Max	
<b>Bypass Diode</b>									
Forward voltage	V <sub>F</sub>			35	T <sub>J</sub> =25°C T <sub>J</sub> =125°C		1,16 1,11	1,21	V
Threshold voltage (for power loss calc. only)	V <sub>to</sub>			35	T <sub>J</sub> =25°C T <sub>J</sub> =125°C		0,90 0,76		V
Slope resistance (for power loss calc. only)	r <sub>t</sub>			35	T <sub>J</sub> =25°C T <sub>J</sub> =125°C		0,01 0,01		Ω
Reverse current	I <sub>r</sub>		1600		T <sub>J</sub> =25°C T <sub>J</sub> =125°C			0,05	mA
Thermal resistance chip to heatsink per chip	R <sub>thJH</sub>	Thermal grease thickness≤50um λ = 1 W/mK					1,53		K/W
<b>Input Boost IGBT</b>									
Gate emitter threshold voltage	V <sub>GE(th)</sub>			0,0008	T <sub>J</sub> =25°C T <sub>J</sub> =125°C	4,1	4,9	5,7	V
Collector-emitter saturation voltage	V <sub>CE(sat)</sub>		15	0	50	T <sub>J</sub> =25°C T <sub>J</sub> =125°C	1,94 2,22	2	V
Collector-emitter cut-off	I <sub>CES</sub>		0	600		T <sub>J</sub> =25°C T <sub>J</sub> =125°C		0,04	mA
Gate-emitter leakage current	I <sub>GES</sub>		20			T <sub>J</sub> =25°C T <sub>J</sub> =125°C		100	nA
Integrated Gate resistor	R <sub>gint</sub>						none		Ω
Turn-on delay time	t <sub>d(on)</sub>	R <sub>goff</sub> =4 Ω R <sub>gon</sub> =4 Ω	±15	400	50	T <sub>J</sub> =25°C T <sub>J</sub> =125°C	23 21		ns
Rise time	t <sub>r</sub>					T <sub>J</sub> =25°C T <sub>J</sub> =125°C	13 14		
Turn-off delay time	t <sub>d(off)</sub>					T <sub>J</sub> =25°C T <sub>J</sub> =125°C	185 207		
Fall time	t <sub>f</sub>					T <sub>J</sub> =25°C T <sub>J</sub> =125°C	5 7		
Turn-on energy loss per pulse	E <sub>on</sub>					T <sub>J</sub> =25°C T <sub>J</sub> =125°C	0,62 0,96		mWs
Turn-off energy loss per pulse	E <sub>off</sub>					T <sub>J</sub> =25°C T <sub>J</sub> =125°C	0,47 0,71		
Input capacitance	C <sub>ies</sub>	f=1MHz	0	25	T <sub>J</sub> =25°C		3140		pF
Output capacitance	C <sub>oss</sub>						200		
Reverse transfer capacitance	C <sub>rss</sub>						93		
Gate charge	Q <sub>Gate</sub>	f=1MHz	0	25	T <sub>J</sub> =25°C		310		nC
Thermal resistance chip to heatsink per chip	R <sub>thJH</sub>	Thermal grease thickness≤50um λ = 1 W/mK					1,15		K/W
<b>Input Boost Inverse Diode</b>									
Diode forward voltage	V <sub>F</sub>			10	T <sub>J</sub> =25°C T <sub>J</sub> =125°C	1,25	1,67 1,56	1,95	V
Thermal resistance chip to heatsink per chip	R <sub>thJH</sub>	Thermal grease thickness≤50um λ = 1 W/mK					2,44		K/W
<b>Input Boost Diode</b>									
Forward voltage	V <sub>F</sub>			30	T <sub>J</sub> =25°C T <sub>J</sub> =125°C		2,34 2,01	2,6	V
Reverse leakage current	I <sub>rm</sub>		±15	400	50	T <sub>J</sub> =25°C T <sub>J</sub> =125°C		100	μA
Peak recovery current	I <sub>RRM</sub>	R <sub>gon</sub> =4 Ω	±15	400	50	T <sub>J</sub> =25°C T <sub>J</sub> =125°C	47 72		A
Reverse recovery time	t <sub>rr</sub>					T <sub>J</sub> =25°C T <sub>J</sub> =125°C	15 29		ns
Reverse recovery charge	Q <sub>rr</sub>					T <sub>J</sub> =25°C T <sub>J</sub> =125°C	0,51 1,23		μC
Reverse recovered energy	E <sub>rec</sub>					T <sub>J</sub> =25°C T <sub>J</sub> =125°C	0,07 0,16		mWs
Peak rate of fall of recovery current	di(rec)max /dt					T <sub>J</sub> =25°C T <sub>J</sub> =125°C	15400 10220		A/μs
Thermal resistance chip to heatsink per chip	R <sub>thJH</sub>	Thermal grease thickness≤50um λ = 1 W/mK					1,76		K/W

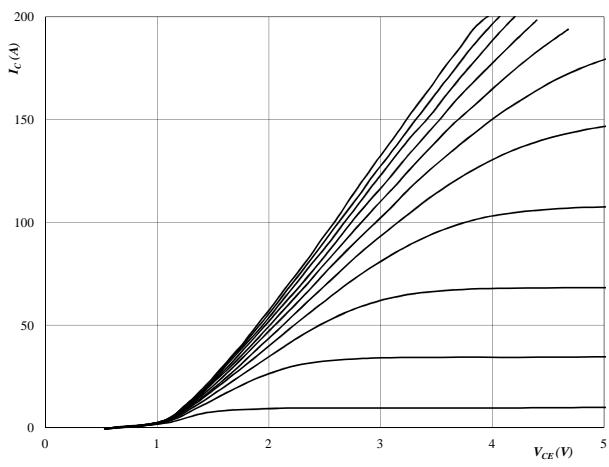
### Characteristic Values

Parameter	Symbol	Conditions					Value			Unit
			V <sub>GE</sub> [V] or V <sub>GS</sub> [V]	V <sub>I</sub> [V] or V <sub>CE</sub> [V] or V <sub>DS</sub> [V]	I <sub>C</sub> [A] or I <sub>F</sub> [A] or I <sub>D</sub> [A]	T <sub>J</sub>	Min	Typ	Max	
<b>H-Bridge IGBT</b>										
Gate emitter threshold voltage	V <sub>GE(th)</sub>	V <sub>GE</sub> =V <sub>CE</sub>			0,0008	T <sub>J</sub> =25°C T <sub>J</sub> =125°C	4,1	4,9	5,7	V
Collector-emitter saturation voltage	V <sub>CE(sat)</sub>		15	0	50	T <sub>J</sub> =25°C T <sub>J</sub> =125°C		1,94 2,22	2	V
Collector-emitter cut-off incl diode	I <sub>CES</sub>		0	600		T <sub>J</sub> =25°C T <sub>J</sub> =125°C			0,04	mA
Gate-emitter leakage current	I <sub>GES</sub>		20			T <sub>J</sub> =25°C T <sub>J</sub> =125°C			100	nA
Integrated Gate resistor	R <sub>gint</sub>					T <sub>J</sub> =25°C T <sub>J</sub> =125°C		none		Ω
Turn-on delay time	t <sub>d(on)</sub>	R <sub>goff</sub> =4 Ω R <sub>gon</sub> =4 Ω	±15	400	50	T <sub>J</sub> =25°C T <sub>J</sub> =125°C		22 22		ns
Rise time	t <sub>r</sub>					T <sub>J</sub> =25°C T <sub>J</sub> =125°C		13 14		ns
Turn-off delay time	t <sub>d(off)</sub>					T <sub>J</sub> =25°C T <sub>J</sub> =125°C		182 204		ns
Fall time	t <sub>f</sub>					T <sub>J</sub> =25°C T <sub>J</sub> =125°C		4 7		ns
Turn-on energy loss per pulse	E <sub>on</sub>					T <sub>J</sub> =25°C T <sub>J</sub> =125°C		0,61 0,89		mWs
Turn-off energy loss per pulse	E <sub>off</sub>					T <sub>J</sub> =25°C T <sub>J</sub> =125°C		0,42 0,67		mWs
Input capacitance	C <sub>ies</sub>							3140		pF
Output capacitance	C <sub>oss</sub>					T <sub>J</sub> =25°C		200		pF
Reverse transfer capacitance	C <sub>rss</sub>							93		pF
Gate charge	Q <sub>Gate</sub>		±15	480	50	T <sub>J</sub> =25°C		310		nC
Thermal resistance chip to heatsink per chip	R <sub>thJH</sub>	Thermal grease thickness≤50um λ = 1 W/mK						1,15		K/W
<b>H-Bridge Diode</b>										
Diode forward voltage	V <sub>F</sub>				50	T <sub>J</sub> =25°C T <sub>J</sub> =125°C		2,33 2,01	2,6	V
Peak reverse recovery current	I <sub>RRM</sub>	R <sub>gon</sub> =4 Ω	±15	400	50	T <sub>J</sub> =25°C T <sub>J</sub> =125°C		51 75		A
Reverse recovery time	t <sub>rr</sub>					T <sub>J</sub> =25°C T <sub>J</sub> =125°C		16 29		ns
Reverse recovered charge	Q <sub>rr</sub>					T <sub>J</sub> =25°C T <sub>J</sub> =125°C		0,49 1,24		μC
Peak rate of fall of recovery current	di(rec)max/dt					T <sub>J</sub> =25°C T <sub>J</sub> =125°C		14960 10600		A/μs
Reverse recovery energy	E <sub>rec</sub>					T <sub>J</sub> =25°C T <sub>J</sub> =125°C		0,06 0,18		mWs
Thermal resistance chip to heatsink per chip	R <sub>thJH</sub>	Thermal grease thickness≤50um λ = 1 W/mK						1,76		K/W
<b>DC link Capacitor</b>										
C value	C							47		nF
<b>Thermistor</b>										
Rated resistance	R					T=25°C		22000		Ω
Deviation of R25	ΔR/R	R100=1486 Ω				T=25°C	-5		+5	%
Power dissipation	P					T=25°C		200		mW
Power dissipation constant						T <sub>J</sub> =25°C		2		mW/K
B-value	B <sub>(25/50)</sub>	Tol. ±3%				T <sub>J</sub> =25°C		3950		K
B-value	B <sub>(25/100)</sub>	Tol. ±3%				T <sub>J</sub> =25°C		3996		K
Vincotech NTC Reference									B	

## H-Bridge

**Figure 1**  
**Typical output characteristics**  
 $I_C = f(V_{CE})$

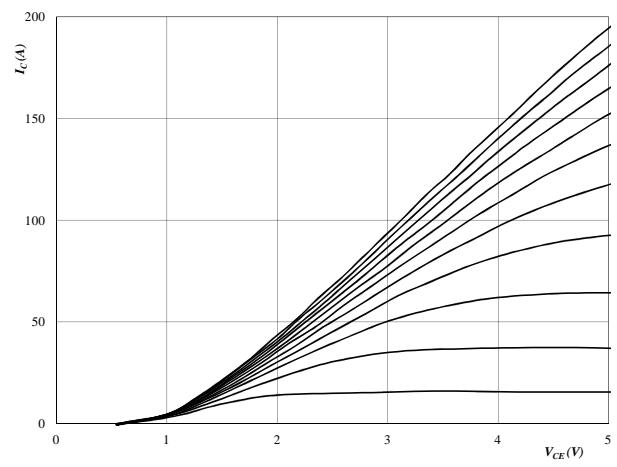
IGBT



**At**  
 $t_p = 250 \mu s$   
 $T_j = 25^\circ C$   
 $V_{GE}$  from 7 V to 17 V in steps of 1 V

**Figure 2**  
**Typical output characteristics**  
 $I_C = f(V_{CE})$

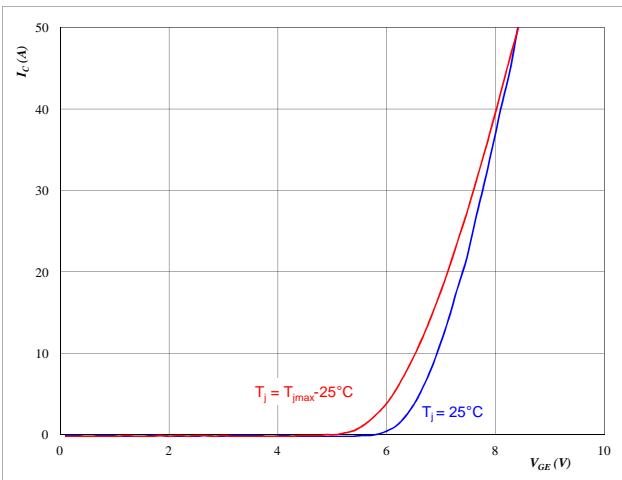
IGBT



**At**  
 $t_p = 250 \mu s$   
 $T_j = 125^\circ C$   
 $V_{GE}$  from 7 V to 17 V in steps of 1 V

**Figure 3**  
**Typical transfer characteristics**  
 $I_C = f(V_{GE})$

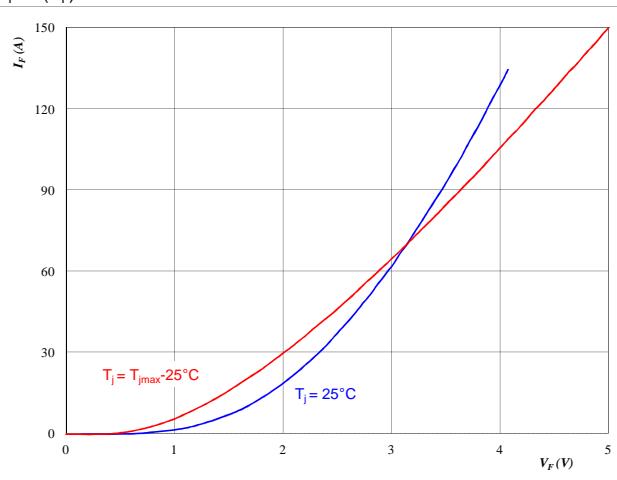
IGBT



**At**  
 $t_p = 250 \mu s$   
 $V_{CE} = 10 V$

**Figure 4**  
**Typical diode forward current as a function of forward voltage**  
 $I_F = f(V_F)$

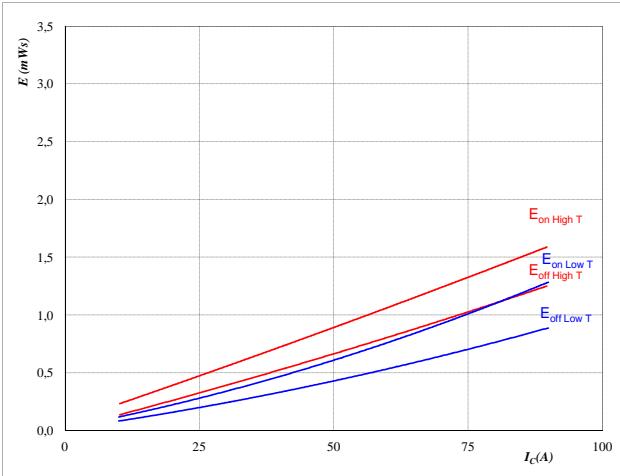
FWD



**At**  
 $t_p = 250 \mu s$

## H-Bridge

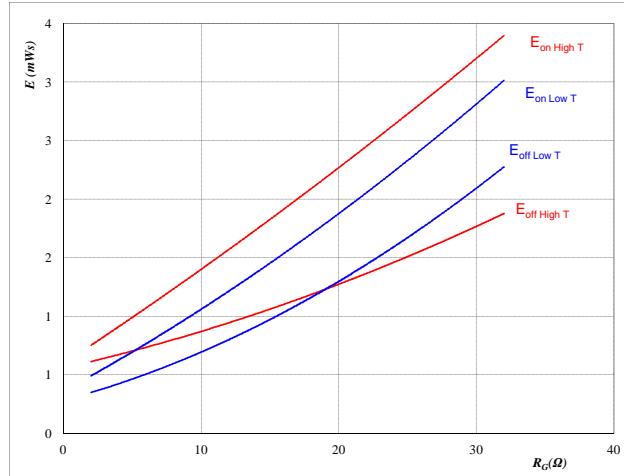
**Figure 5**  
**Typical switching energy losses  
as a function of collector current**  
 $E = f(I_C)$



With an inductive load at

T<sub>j</sub> = 25/125 °C  
V<sub>CE</sub> = 400 V  
V<sub>GE</sub> = 15 V  
R<sub>gon</sub> = 4 Ω  
R<sub>goff</sub> = 4 Ω

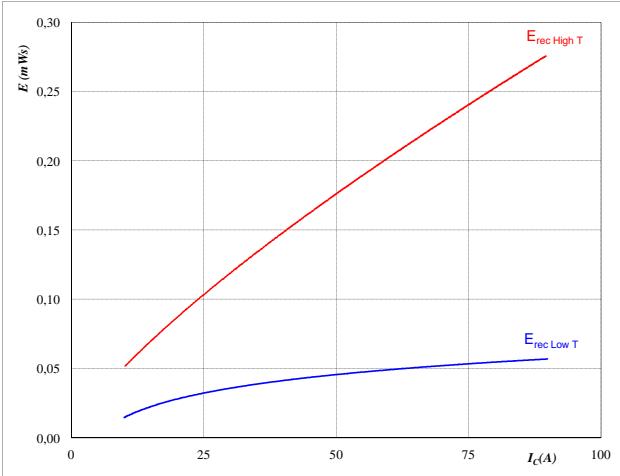
**Figure 6**  
**Typical switching energy losses  
as a function of gate resistor**  
 $E = f(R_G)$



With an inductive load at

T<sub>j</sub> = 25/125 °C  
V<sub>CE</sub> = 400 V  
V<sub>GE</sub> = 15 V  
I<sub>C</sub> = 50 A

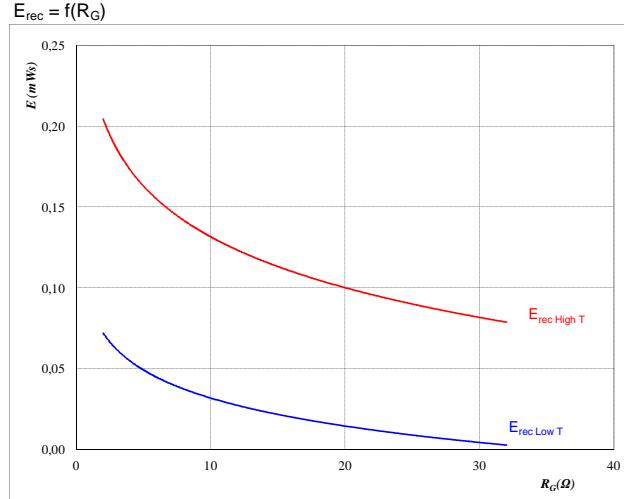
**Figure 7**  
**Typical reverse recovery energy loss  
as a function of collector current**  
 $E_{rec} = f(I_C)$



With an inductive load at

T<sub>j</sub> = 25/125 °C  
V<sub>CE</sub> = 400 V  
V<sub>GE</sub> = 15 V  
R<sub>gon</sub> = 4 Ω

**Figure 8**  
**Typical reverse recovery energy loss  
as a function of gate resistor**  
 $E_{rec} = f(R_G)$



With an inductive load at

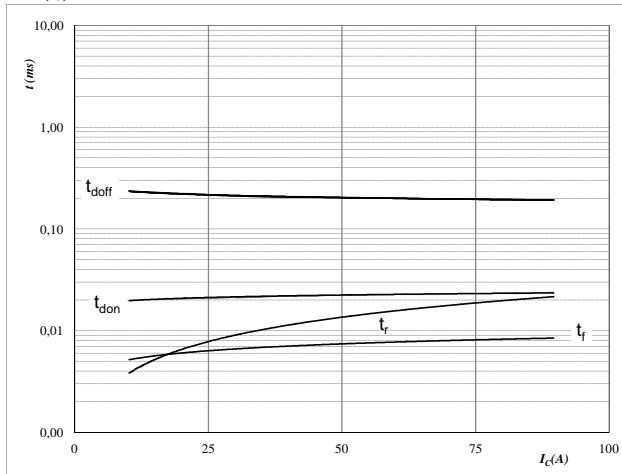
T<sub>j</sub> = 25/125 °C  
V<sub>CE</sub> = 400 V  
V<sub>GE</sub> = 15 V  
I<sub>C</sub> = 50 A

## H-Bridge

**Figure 9**

Typical switching times as a function of collector current

$$t = f(I_C)$$



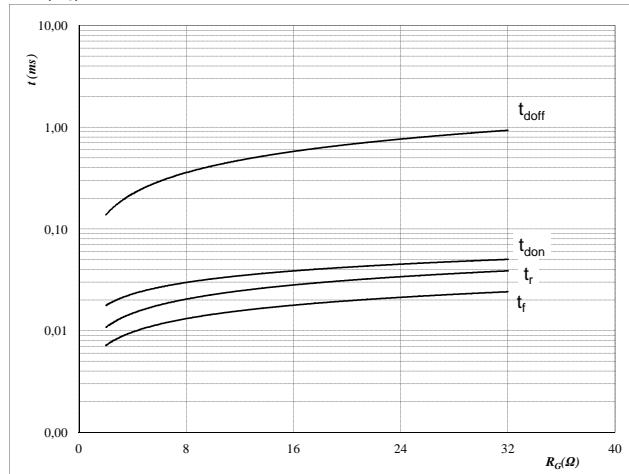
With an inductive load at

T <sub>j</sub> =	125	°C
V <sub>CE</sub> =	400	V
V <sub>GE</sub> =	15	V
R <sub>gon</sub> =	4	Ω
R <sub>goff</sub> =	4	Ω

**Figure 10**

Typical switching times as a function of gate resistor

$$t = f(R_G)$$



With an inductive load at

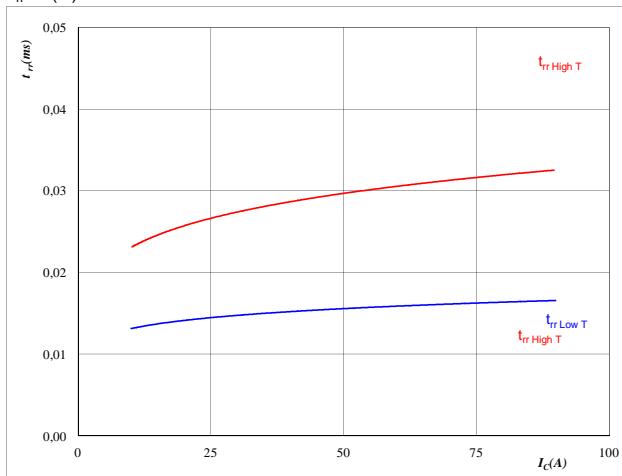
T <sub>j</sub> =	125	°C
V <sub>CE</sub> =	400	V
V <sub>GE</sub> =	15	V
I <sub>C</sub> =	50	A

**Figure 11**

FWD

Typical reverse recovery time as a function of collector current

$$t_{rr} = f(I_C)$$



At

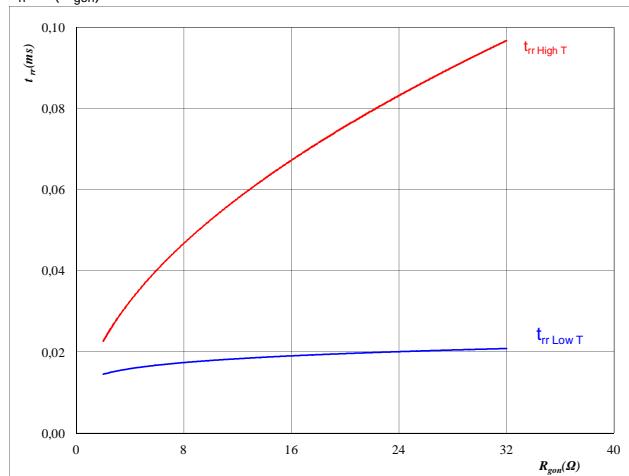
T <sub>j</sub> =	25/125	°C
V <sub>CE</sub> =	400	V
V <sub>GE</sub> =	15	V
R <sub>gon</sub> =	4	Ω

**Figure 12**

FWD

Typical reverse recovery time as a function of IGBT turn on gate resistor

$$t_{rr} = f(R_{gon})$$



At

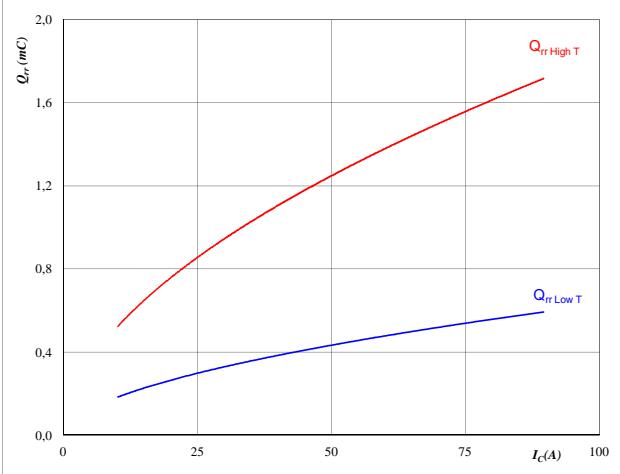
T <sub>j</sub> =	25/125	°C
V <sub>R</sub> =	400	V
I <sub>F</sub> =	50	A
V <sub>GE</sub> =	15	V

## H-Bridge

**Figure 13**

Typical reverse recovery charge as a function of collector current

$$Q_{rr} = f(I_C)$$

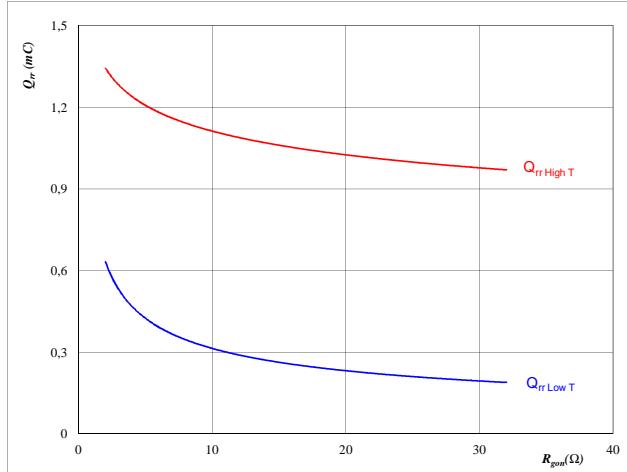
**FWD**

**At**

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{CE} &= 400 \quad \text{V} \\ V_{GE} &= 15 \quad \text{V} \\ R_{gon} &= 4 \quad \Omega \end{aligned}$$

**Figure 14**

Typical reverse recovery charge as a function of IGBT turn on gate resistor

$$Q_{rr} = f(R_{gon})$$

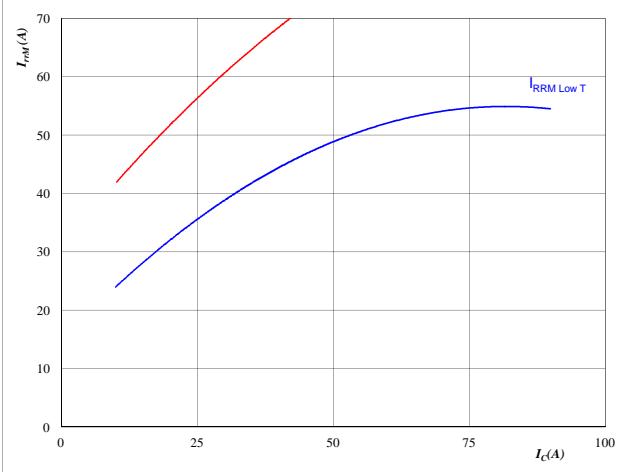
**FWD**

**At**

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_R &= 400 \quad \text{V} \\ I_F &= 50 \quad \text{A} \\ V_{GE} &= 15 \quad \text{V} \end{aligned}$$

**Figure 15**

Typical reverse recovery current as a function of collector current

$$I_{RRM} = f(I_C)$$

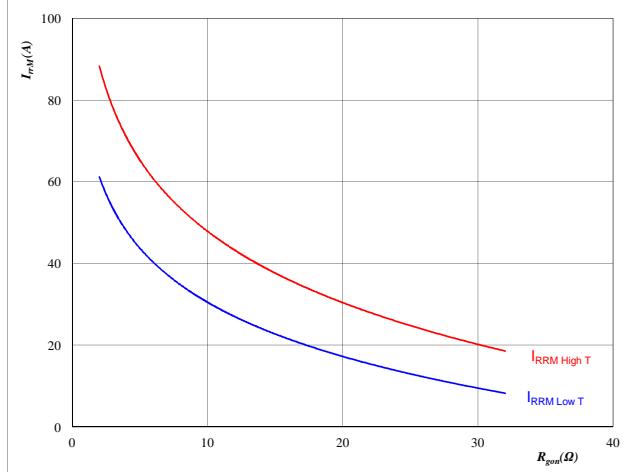
**FWD**

**At**

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{CE} &= 400 \quad \text{V} \\ V_{GE} &= 15 \quad \text{V} \\ R_{gon} &= 4 \quad \Omega \end{aligned}$$

**Figure 16**

Typical reverse recovery current as a function of IGBT turn on gate resistor

$$I_{RRM} = f(R_{gon})$$

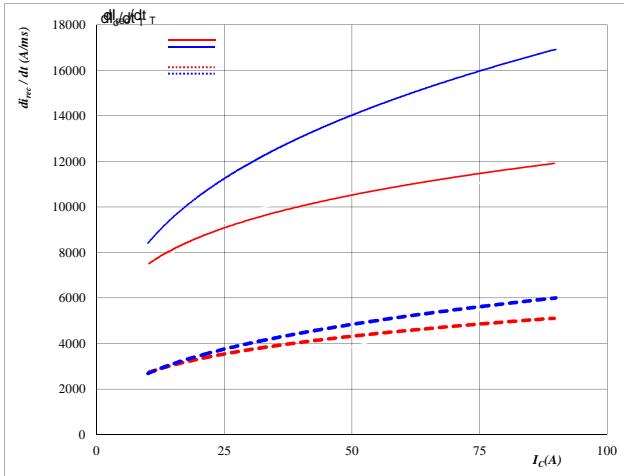
**FWD**

**At**

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_R &= 400 \quad \text{V} \\ I_F &= 50 \quad \text{A} \\ V_{GE} &= 15 \quad \text{V} \end{aligned}$$

## H-Bridge

**Figure 17**

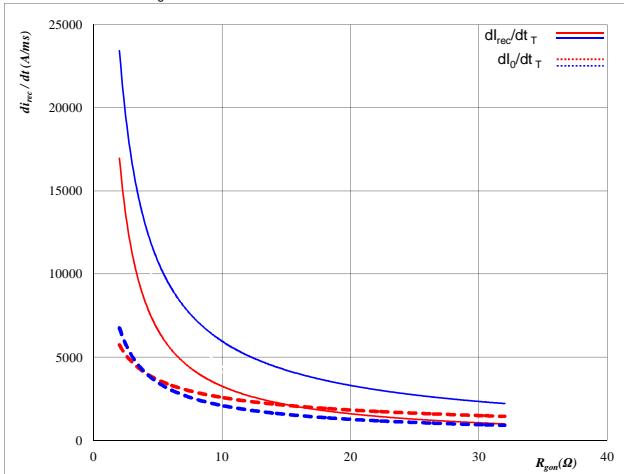
Typical rate of fall of forward  
and reverse recovery current as a  
function of collector current  
 $dI_0/dt, dI_{rec}/dt = f(I_C)$


**At**

$T_J = 25/125 \text{ } ^\circ\text{C}$   
 $V_{CE} = 400 \text{ V}$   
 $V_{GE} = 15 \text{ V}$   
 $R_{gon} = 4 \Omega$

**FWD**
**Figure 18**

Typical rate of fall of forward  
and reverse recovery current as a  
function of IGBT turn on gate resistor  
 $dI_0/dt, dI_{rec}/dt = f(R_{gon})$

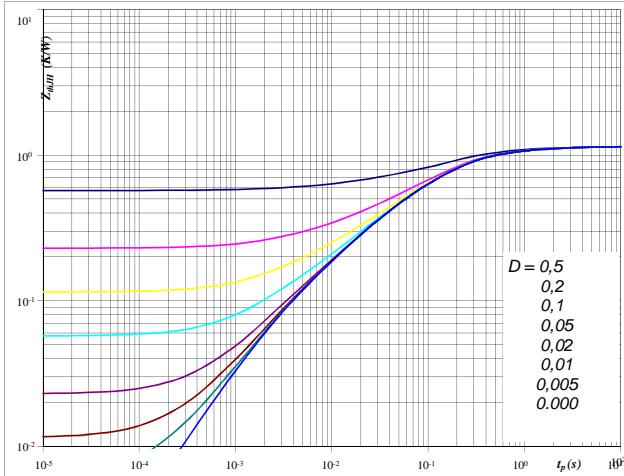

**At**

$T_J = 25/125 \text{ } ^\circ\text{C}$   
 $V_R = 400 \text{ V}$   
 $I_F = 50 \text{ A}$   
 $V_{GE} = 15 \text{ V}$

**Figure 19**

IGBT transient thermal impedance  
as a function of pulse width

$$Z_{thJH} = f(t_p)$$

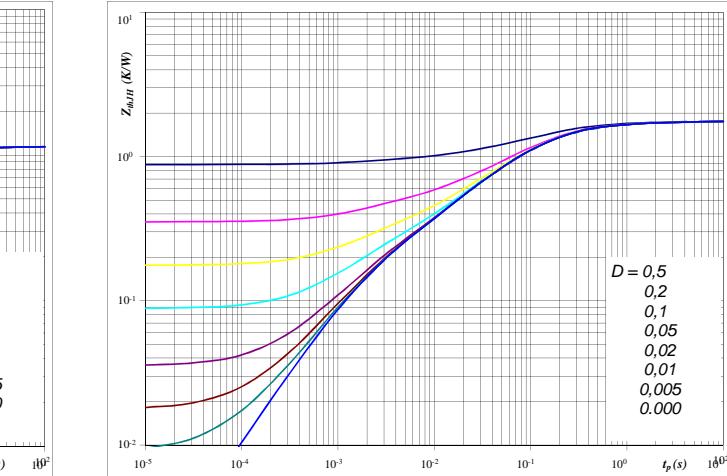

**IGBT thermal model values**

R (C/W)	Tau (s)
0,09	2,0E+00
0,33	3,2E-01
0,51	9,4E-02
0,16	1,5E-02
0,05	2,3E-03

**Figure 20**

FWD transient thermal impedance  
as a function of pulse width

$$Z_{thJH} = f(t_p)$$


**FWD thermal model values**

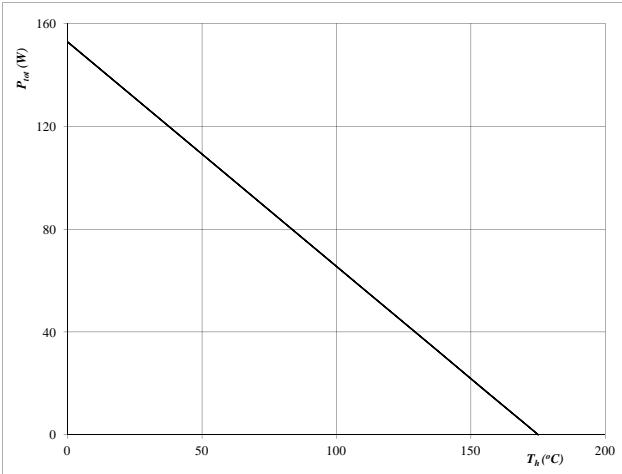
R (C/W)	Tau (s)
0,06	4,8E+00
0,17	7,6E-01
0,70	1,6E-01
0,53	5,1E-02
0,19	1,1E-02
0,12	1,6E-03

## H-Bridge

**Figure 21**

**Power dissipation as a function of heatsink temperature**

$$P_{\text{tot}} = f(T_h)$$

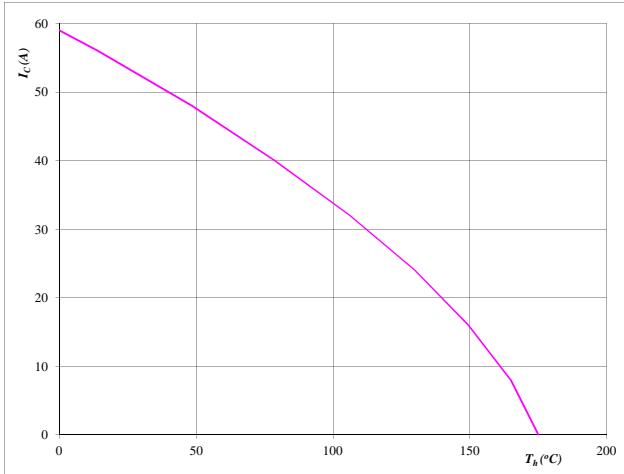

**At**

$$T_j = 175 \quad ^\circ\text{C}$$

**IGBT**
**Figure 22**

**Collector current as a function of heatsink temperature**

$$I_C = f(T_h)$$


**At**

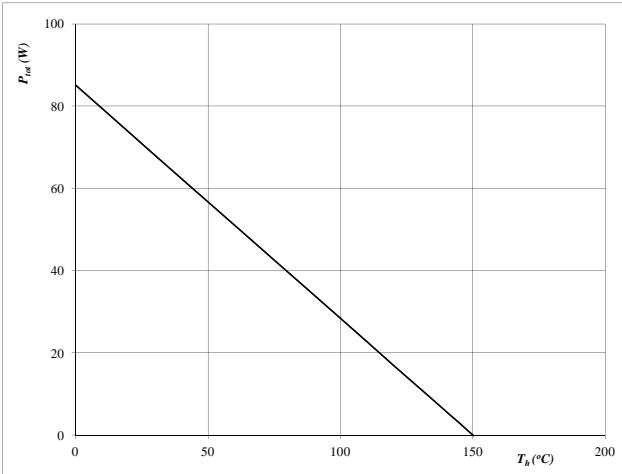
$$T_j = 175 \quad ^\circ\text{C}$$

$$V_{GE} = 15 \quad \text{V}$$

**Figure 23**

**Power dissipation as a function of heatsink temperature**

$$P_{\text{tot}} = f(T_h)$$

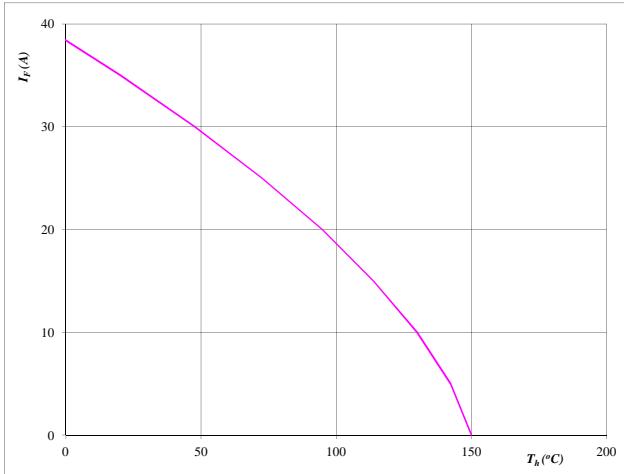

**At**

$$T_j = 150 \quad ^\circ\text{C}$$

**FWD**
**Figure 24**

**Forward current as a function of heatsink temperature**

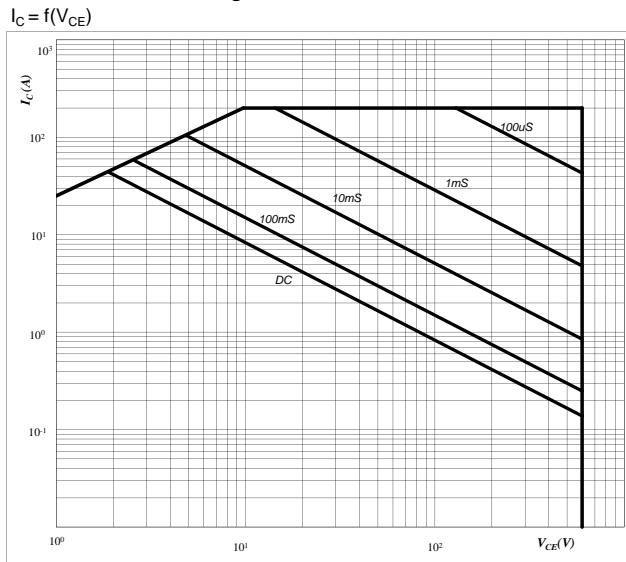
$$I_F = f(T_h)$$


**At**

$$T_j = 150 \quad ^\circ\text{C}$$

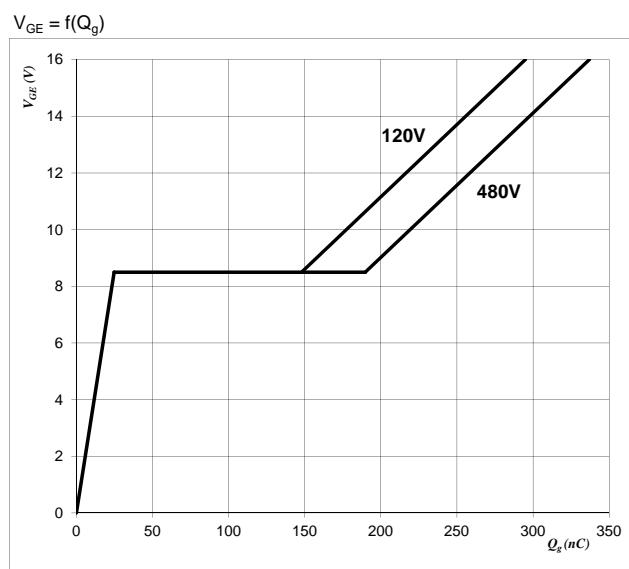
## H-Bridge

**Figure 25**  
**Safe operating area as a function  
of collector-emitter voltage**



**At**  
D = single pulse  
Th = 80 °C  
V<sub>GE</sub> = 15 V  
T<sub>j</sub> = T<sub>jmax</sub> °C

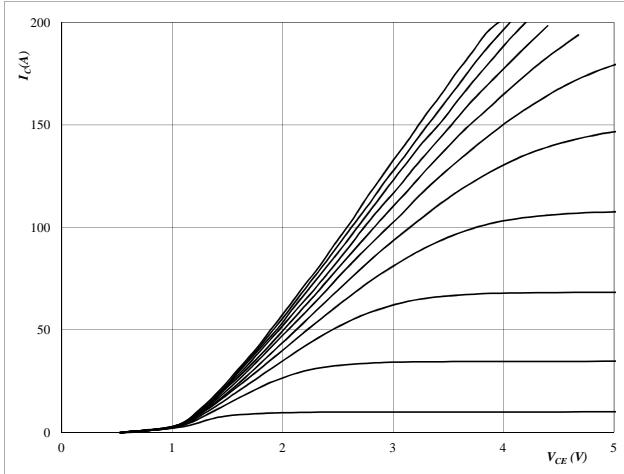
**Figure 26**  
**Gate voltage vs Gate charge**



**At**  
I<sub>C</sub> = 50 A

## INPUT BOOST

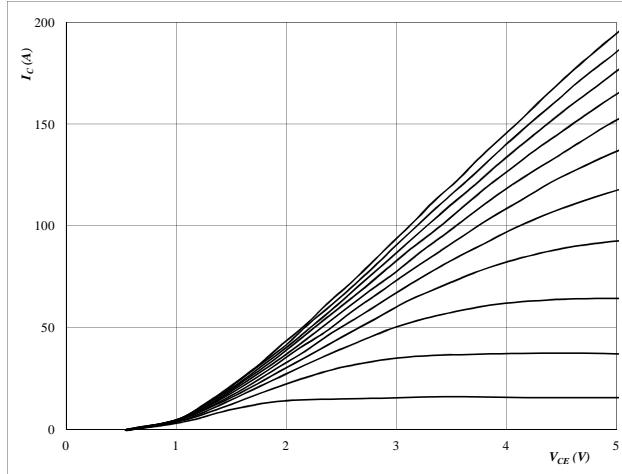
**Figure 1**  
**Typical output characteristics**  
 $I_D = f(V_{DS})$



**At**  
 $t_p = 250 \mu s$   
 $T_j = 25^\circ C$   
 $V_{GS}$  from 7 V to 17 V in steps of 1 V

BOOST IGBT

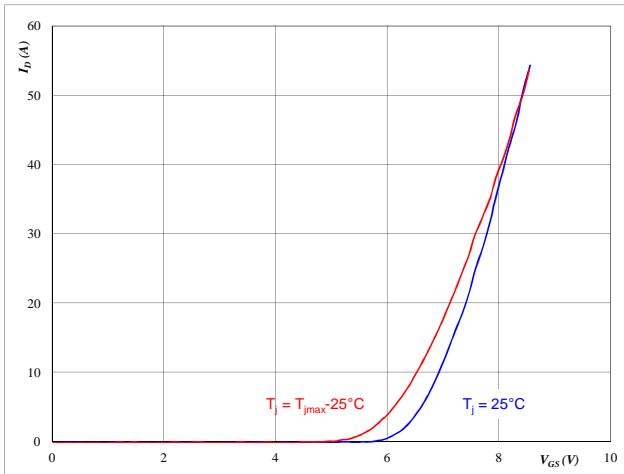
**Figure 2**  
**Typical output characteristics**  
 $I_D = f(V_{DS})$



**At**  
 $t_p = 250 \mu s$   
 $T_j = 125^\circ C$   
 $V_{GS}$  from 7 V to 17 V in steps of 1 V

BOOST IGBT

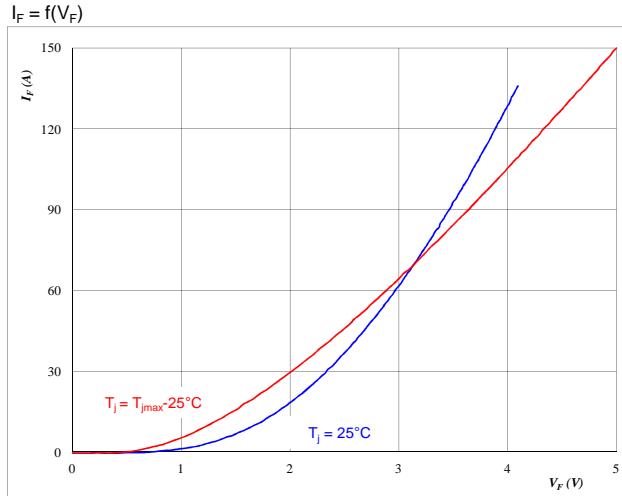
**Figure 3**  
**Typical transfer characteristics**  
 $I_D = f(V_{GS})$



**At**  
 $t_p = 250 \mu s$   
 $V_{DS} = 10 V$

BOOST IGBT

**Figure 4**  
**Typical diode forward current as a function of forward voltage**  
 $I_F = f(V_F)$



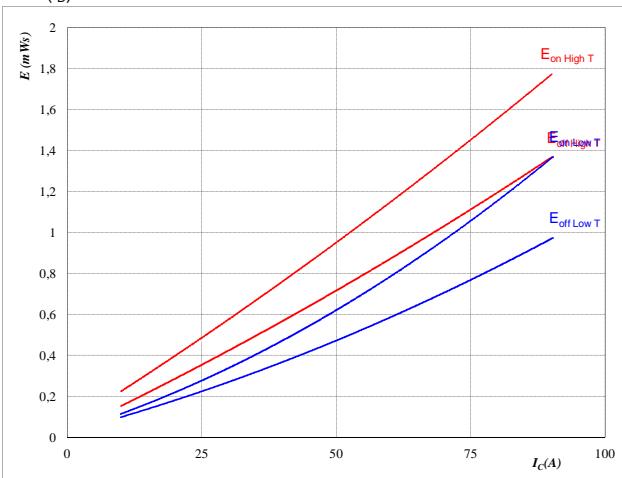
**At**  
 $t_p = 250 \mu s$

## INPUT BOOST

**Figure 5**

Typical switching energy losses  
as a function of collector current

$$E = f(I_D)$$



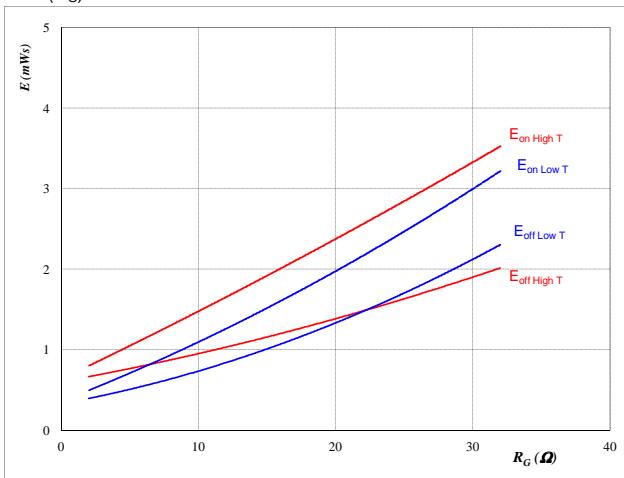
With an inductive load at

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{DS} &= 400 \quad \text{V} \\ V_{GS} &= 15 \quad \text{V} \\ R_{gon} &= 4 \quad \Omega \\ R_{goff} &= 4 \quad \Omega \end{aligned}$$

**BOOST IGBT**
**Figure 6**

Typical switching energy losses  
as a function of gate resistor

$$E = f(R_G)$$



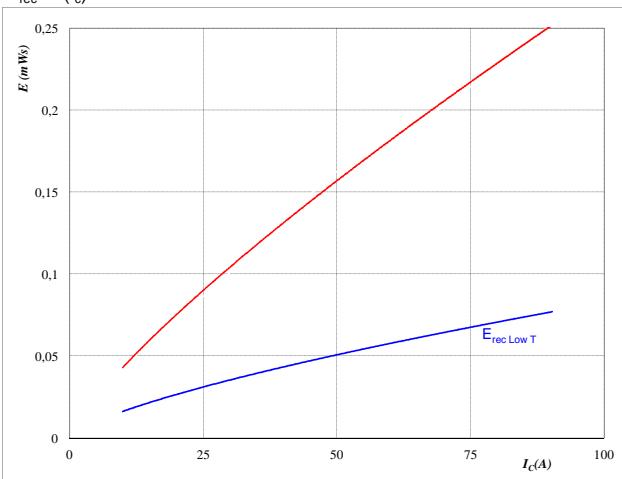
With an inductive load at

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{DS} &= 400 \quad \text{V} \\ V_{GS} &= 15 \quad \text{V} \\ I_D &= 50 \quad \text{A} \end{aligned}$$

**Figure 7**

Typical reverse recovery energy loss  
as a function of collector (drain) current

$$E_{rec} = f(I_c)$$



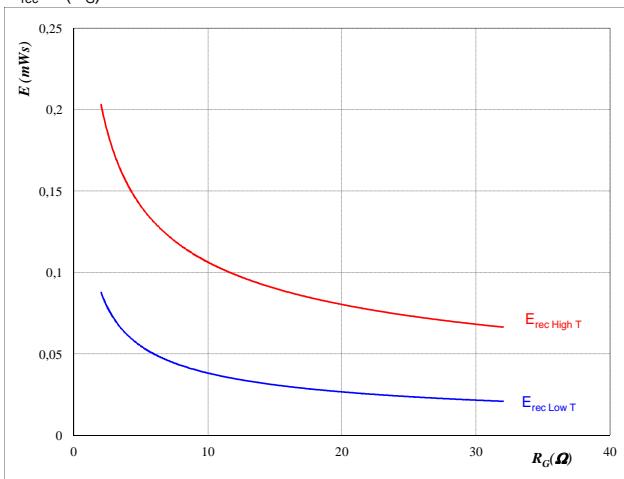
With an inductive load at

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{DS} &= 400 \quad \text{V} \\ V_{GS} &= 15 \quad \text{V} \\ R_{gon} &= 4 \quad \Omega \\ R_{goff} &= 4 \quad \Omega \end{aligned}$$

**BOOST FWD**
**Figure 8**

Typical reverse recovery energy loss  
as a function of gate resistor

$$E_{rec} = f(R_G)$$

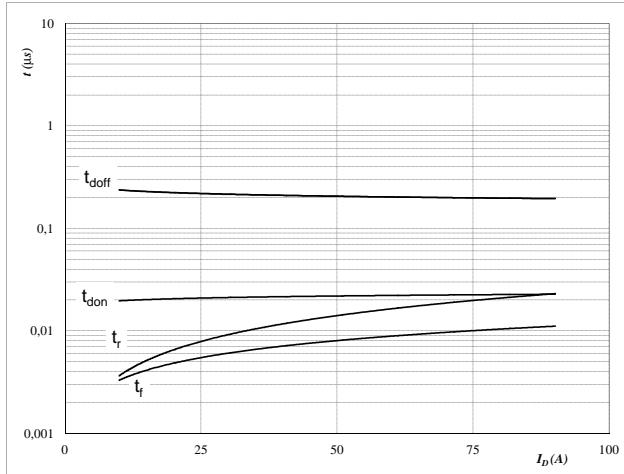


With an inductive load at

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{DS} &= 400 \quad \text{V} \\ V_{GS} &= 15 \quad \text{V} \\ I_D &= 50 \quad \text{A} \end{aligned}$$

## INPUT BOOST

**Figure 9**  
**Typical switching times as a function of collector current**  
 $t = f(I_D)$

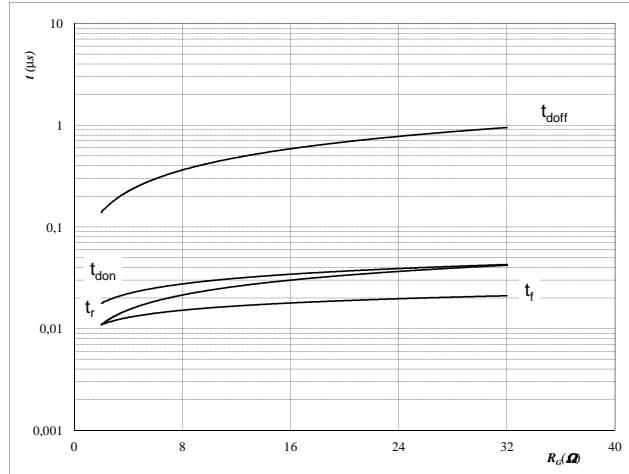


With an inductive load at

T<sub>j</sub> = 125 °C  
V<sub>DS</sub> = 400 V  
V<sub>GS</sub> = 15 V  
R<sub>gon</sub> = 4 Ω  
R<sub>goff</sub> = 4 Ω

**BOOST IGBT**

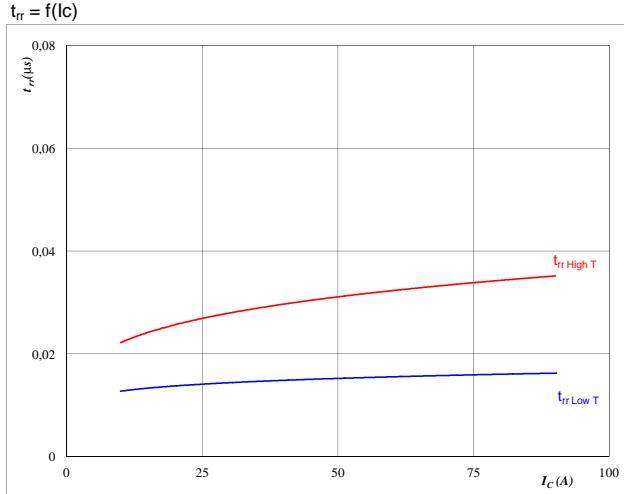
**Figure 10**  
**Typical switching times as a function of gate resistor**  
 $t = f(R_G)$



With an inductive load at

T<sub>j</sub> = 125 °C  
V<sub>DS</sub> = 400 V  
V<sub>GS</sub> = 15 V  
I<sub>C</sub> = 50 A

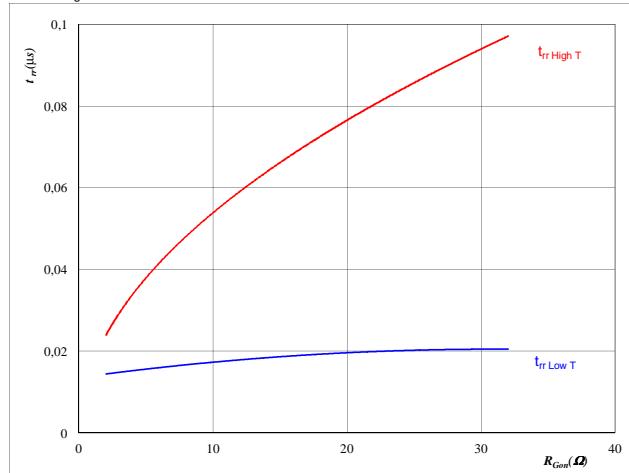
**Figure 11**  
**Typical reverse recovery time as a function of collector current**  
 $t_{rr} = f(I_C)$



**At**  
T<sub>j</sub> = 25/125 °C  
V<sub>CE</sub> = 400 V  
V<sub>GE</sub> = 15 V  
R<sub>gon</sub> = 4 Ω

**BOOST FWD**

**Figure 12**  
**Typical reverse recovery time as a function of IGBT turn on gate resistor**  
 $t_{rr} = f(R_{Gon})$



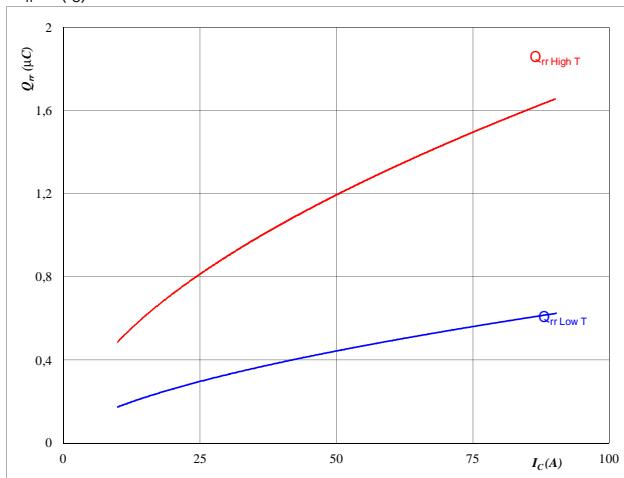
**At**  
T<sub>j</sub> = 25/125 °C  
V<sub>R</sub> = 400 V  
I<sub>F</sub> = 50 A  
V<sub>GS</sub> = 15 V

## INPUT BOOST

**Figure 13**

Typical reverse recovery charge as a function of collector current

$$Q_{rr} = f(I_C)$$

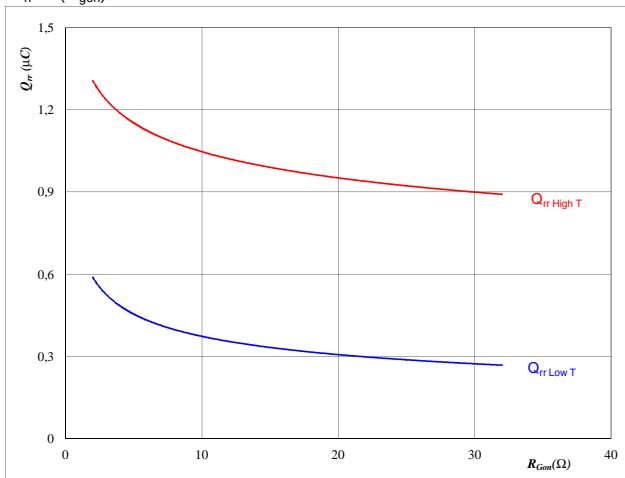

**At**

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{CE} &= 400 \quad \text{V} \\ V_{GE} &= 15 \quad \text{V} \\ R_{gon} &= 4 \quad \Omega \end{aligned}$$

**BOOST FWD**
**Figure 14**

Typical reverse recovery charge as a function of IGBT turn on gate resistor

$$Q_{rr} = f(R_{gon})$$

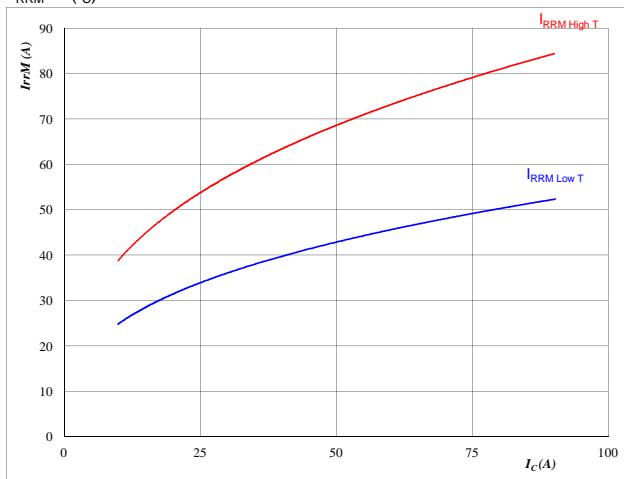

**At**

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_R &= 400 \quad \text{V} \\ I_F &= 50 \quad \text{A} \\ V_{GS} &= 15 \quad \text{V} \end{aligned}$$

**Figure 15**

Typical reverse recovery current as a function of collector current

$$I_{RRM} = f(I_C)$$

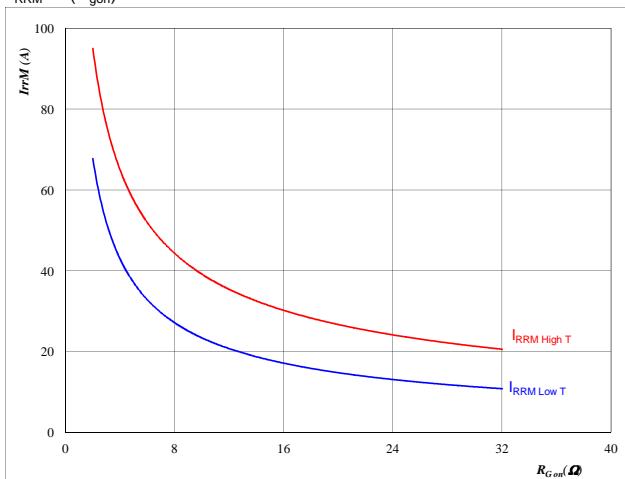

**At**

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_{CE} &= 400 \quad \text{V} \\ V_{GE} &= 15 \quad \text{V} \\ R_{gon} &= 4 \quad \Omega \end{aligned}$$

**BOOST FWD**
**Figure 16**

Typical reverse recovery current as a function of IGBT turn on gate resistor

$$I_{RRM} = f(R_{gon})$$

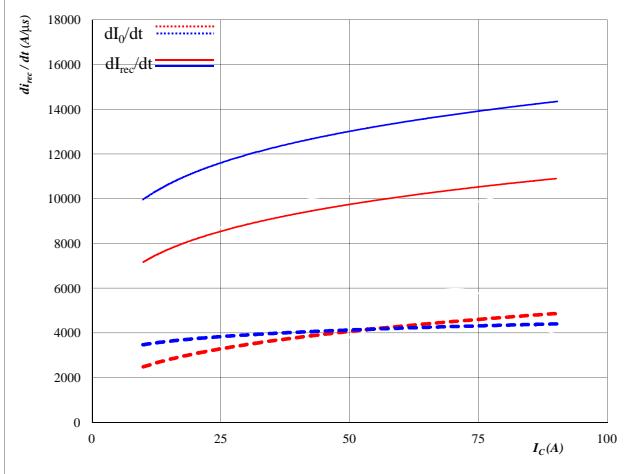

**At**

$$\begin{aligned} T_j &= 25/125 \quad ^\circ\text{C} \\ V_R &= 400 \quad \text{V} \\ I_F &= 50 \quad \text{A} \\ V_{GS} &= 15 \quad \text{V} \end{aligned}$$

## INPUT BOOST

**Figure 17**

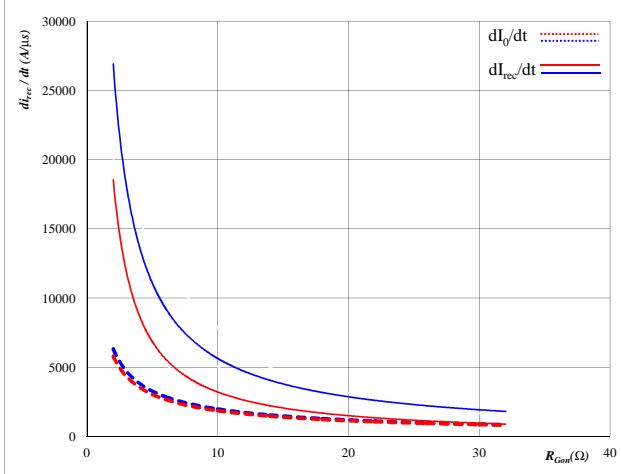
Typical rate of fall of forward  
and reverse recovery current as a  
function of collector current  
 $dI_0/dt, dI_{rec}/dt = f(I_C)$


**At**

$T_j = 25/125 \text{ } ^\circ\text{C}$   
 $V_{CE} = 400 \text{ V}$   
 $V_{GE} = 15 \text{ V}$   
 $R_{gon} = 4 \Omega$

**BOOST FWD**
**Figure 18**

Typical rate of fall of forward  
and reverse recovery current as a  
function of IGBT turn on gate resistor  
 $dI_0/dt, dI_{rec}/dt = f(R_{gon})$

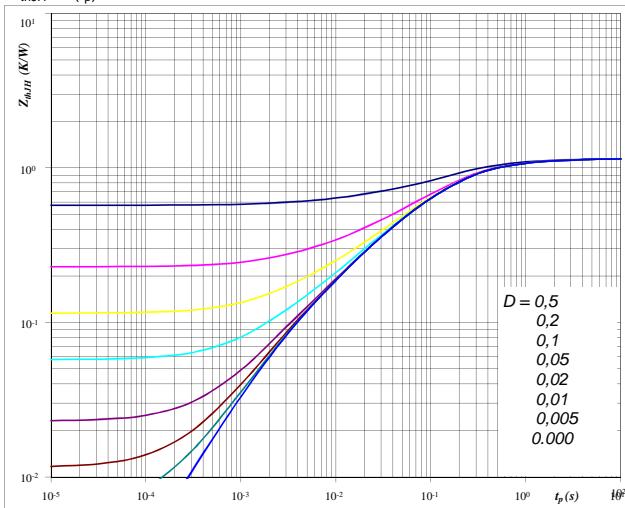

**At**

$T_j = 25/125 \text{ } ^\circ\text{C}$   
 $V_R = 400 \text{ V}$   
 $I_F = 50 \text{ A}$   
 $V_{GS} = 15 \text{ V}$

**Figure 19**

IGBT/MOSFET transient thermal impedance  
as a function of pulse width

$$Z_{thJH} = f(t_p)$$


**At**

$D = t_p / T$   
 $R_{thJH} = 1,15 \text{ K/W}$

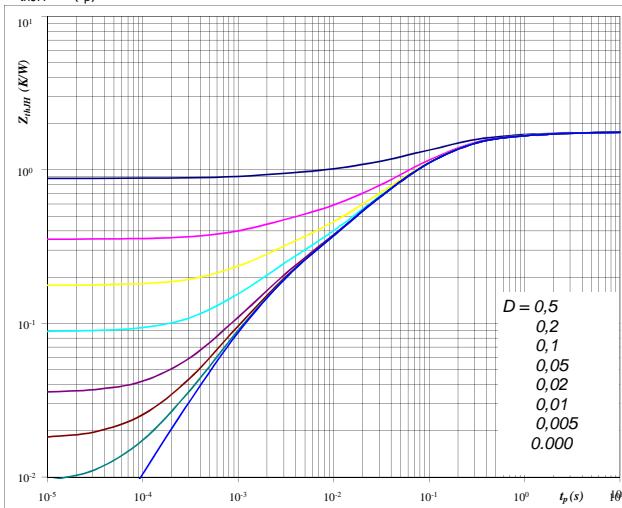
IGBT thermal model values

R (C/W)	Tau (s)
9,49E-02	2,03E+00
3,34E-01	3,24E-01
5,08E-01	9,38E-02
1,62E-01	1,49E-02
4,63E-02	2,34E-03
0,00E+00	0,00E+00

**Figure 20**

FWD transient thermal impedance  
as a function of pulse width

$$Z_{thJH} = f(t_p)$$


**At**

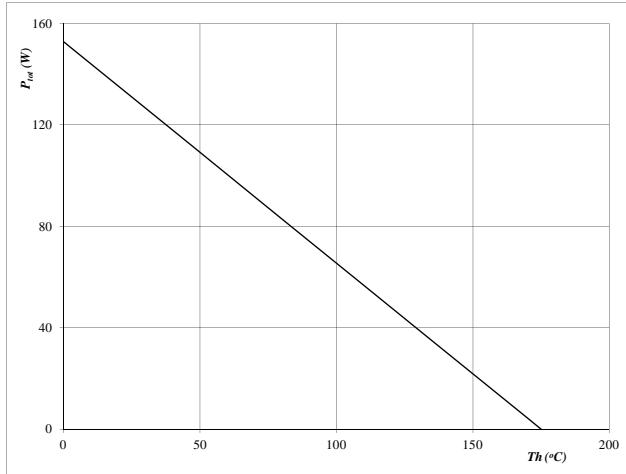
$D = t_p / T$   
 $R_{thJH} = 1,76 \text{ K/W}$

FWD thermal model values

R (C/W)	Tau (s)
5,96E-02	4,76E+00
1,66E-01	7,60E-01
6,99E-01	1,60E-01
5,26E-01	5,15E-02
1,89E-01	1,12E-02
1,23E-01	1,64E-03

## INPUT BOOST

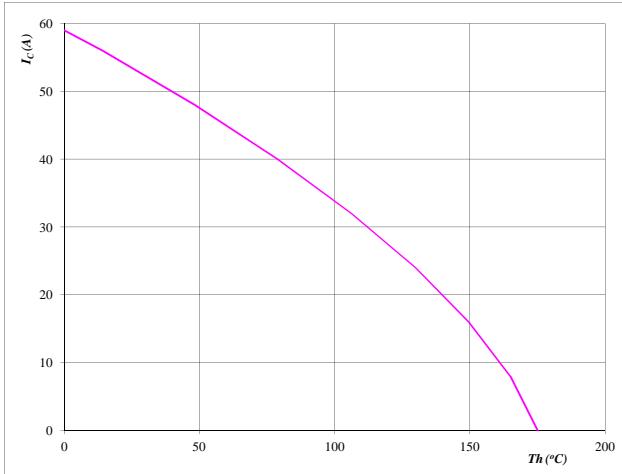
**Figure 21**  
**Power dissipation as a function of heatsink temperature**  
 $P_{\text{tot}} = f(T_h)$



**At**  
T<sub>j</sub> = 175 °C

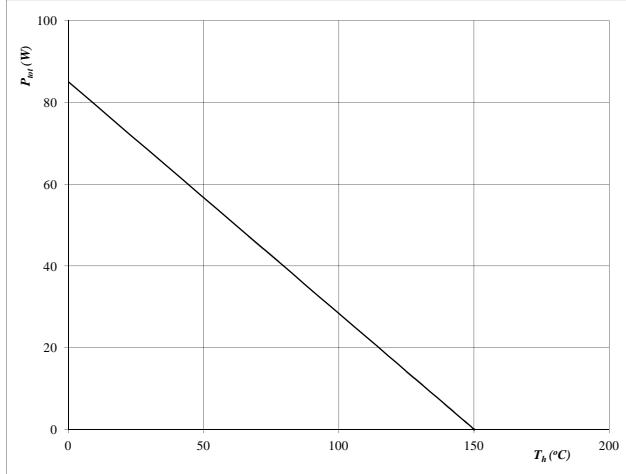
BOOST IGBT

**Figure 22**  
**Collector/Drain current as a function of heatsink temperature**  
 $I_C = f(T_h)$



**At**  
T<sub>j</sub> = 175 °C  
V<sub>GS</sub> = 15 V

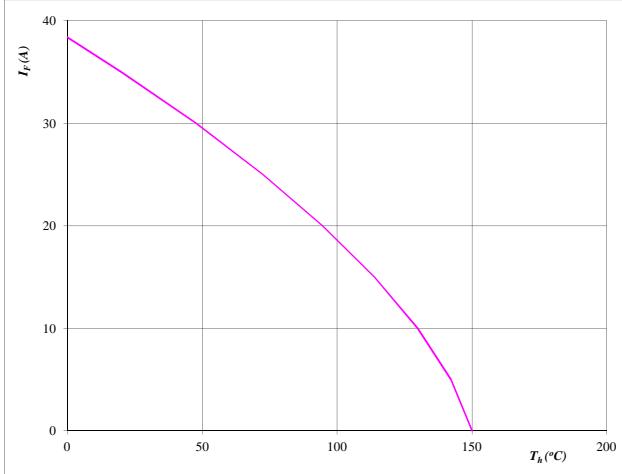
**Figure 23**  
**Power dissipation as a function of heatsink temperature**  
 $P_{\text{tot}} = f(T_h)$



**At**  
T<sub>j</sub> = 150 °C

BOOST FWD

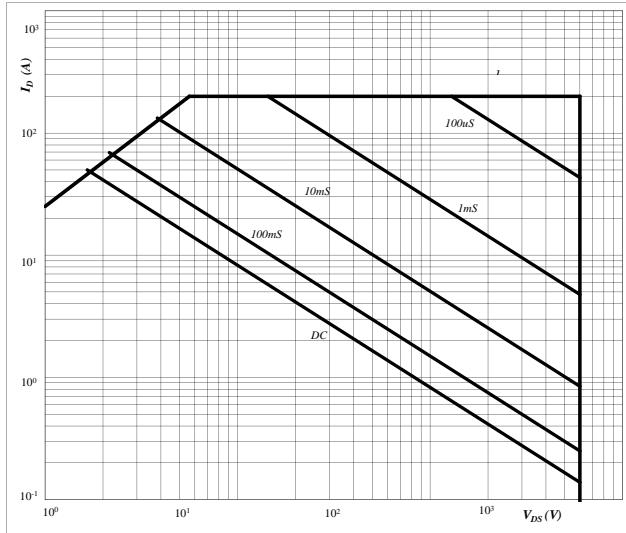
**Figure 24**  
**Forward current as a function of heatsink temperature**  
 $I_F = f(T_h)$



**At**  
T<sub>j</sub> = 150 °C

## INPUT BOOST

**Figure 25**  
**Safe operating area as a function  
of drain-source voltage**  
 $I_D = f(V_{DS})$

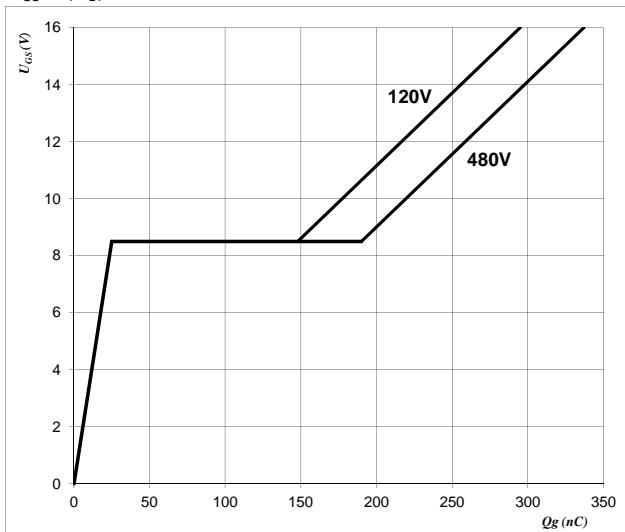


**At**  
D = single pulse  
 $T_h = 80 \text{ } ^\circ\text{C}$   
 $V_{GS} = 15 \text{ V}$   
 $T_j = T_{jmax} \text{ } ^\circ\text{C}$

**BOOST IGBT**

**Figure 26**  
**Gate voltage vs Gate charge**

$$V_{GS} = f(Qg)$$



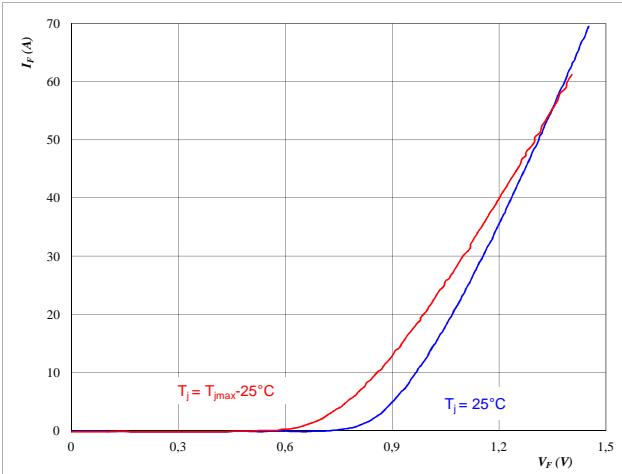
**At**  
 $I_D = 50 \text{ A}$

## Bypass Diode

**Figure 1**

Typical diode forward current as a function of forward voltage

$$I_F = f(V_F)$$

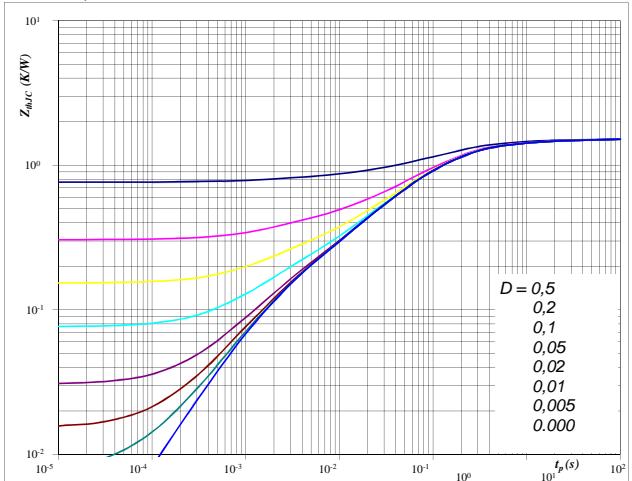

**At**

$$t_p = 250 \mu\text{s}$$

**Bypass diode**
**Figure 2**

Diode transient thermal impedance as a function of pulse width

$$Z_{thJH} = f(t_p)$$


**At**

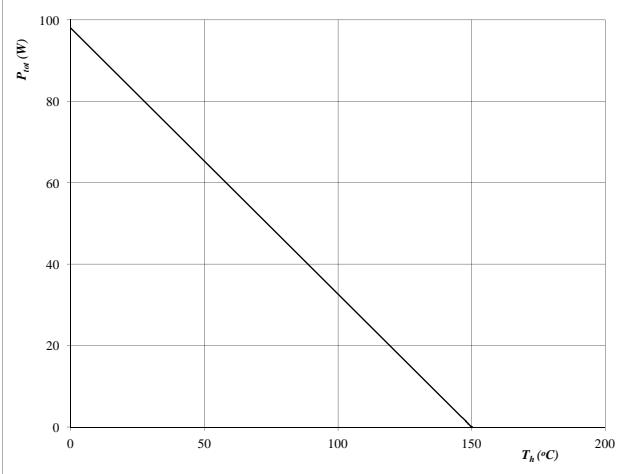
$$D = t_p / T$$

$$R_{thJH} = 1,528 \text{ K/W}$$

**Figure 3**

Power dissipation as a function of heatsink temperature

$$P_{tot} = f(T_h)$$

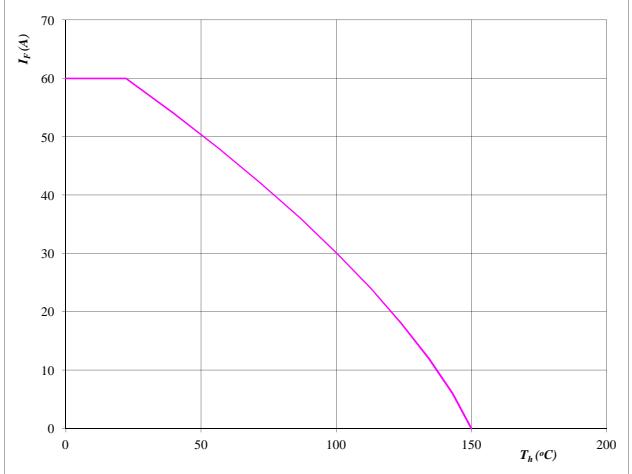

**At**

$$T_j = 150 ^\circ\text{C}$$

**Bypass diode**
**Figure 4**

Forward current as a function of heatsink temperature

$$I_F = f(T_h)$$


**At**

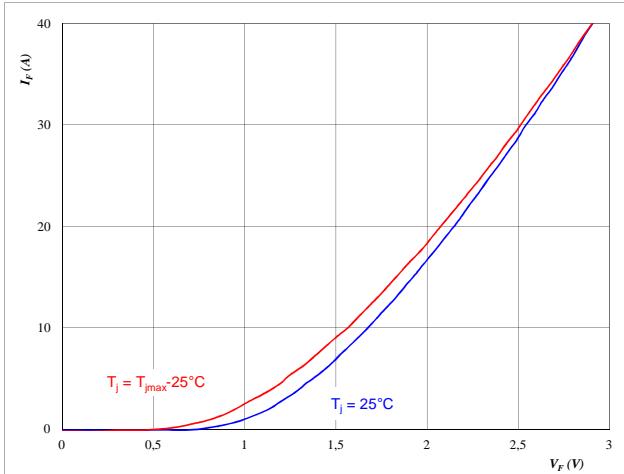
$$T_j = 150 ^\circ\text{C}$$

## INP. BOOST INVERSE DIODE

**Figure 1** INP. BOOST INVERSE DIODE

Typical thyristor forward current as a function of forward voltage

$$I_F = f(V_F)$$



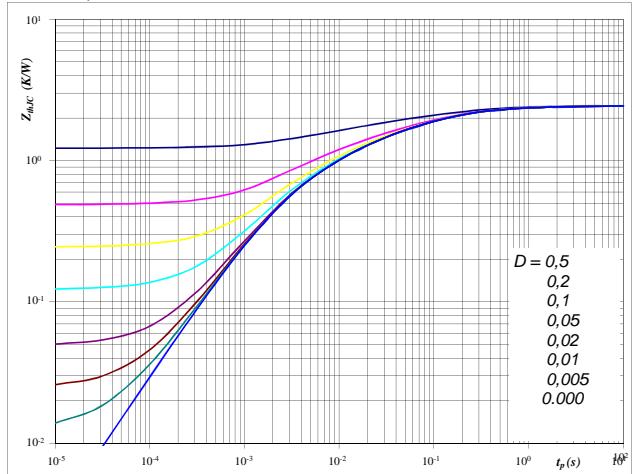
At

$$t_p = 250 \mu\text{s}$$

**Figure 2** INP. BOOST INVERSE DIODE

Thyristor transient thermal impedance as a function of pulse width

$$Z_{thJH} = f(t_p)$$



At

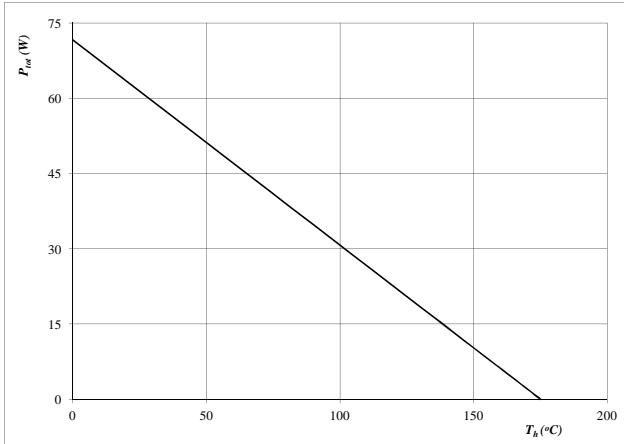
$$D = t_p / T$$

$$R_{thJH} = 2.44 \text{ K/W}$$

**Figure 3** INP. BOOST INVERSE DIODE

Power dissipation as a function of heatsink temperature

$$P_{tot} = f(T_h)$$



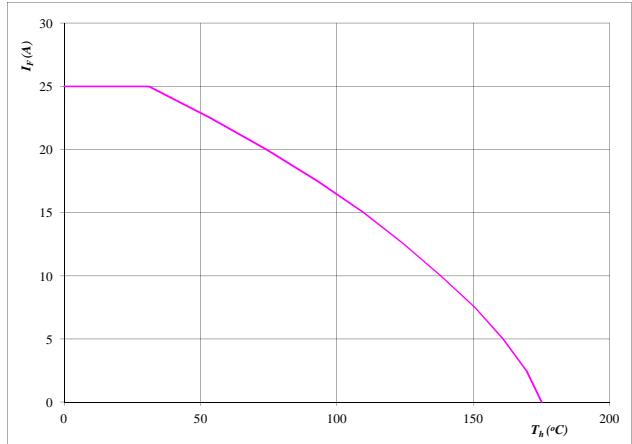
At

$$T_j = 175 \text{ } ^\circ\text{C}$$

**Figure 4** INP. BOOST INVERSE DIODE

Forward current as a function of heatsink temperature

$$I_F = f(T_h)$$



At

$$T_j = 175 \text{ } ^\circ\text{C}$$

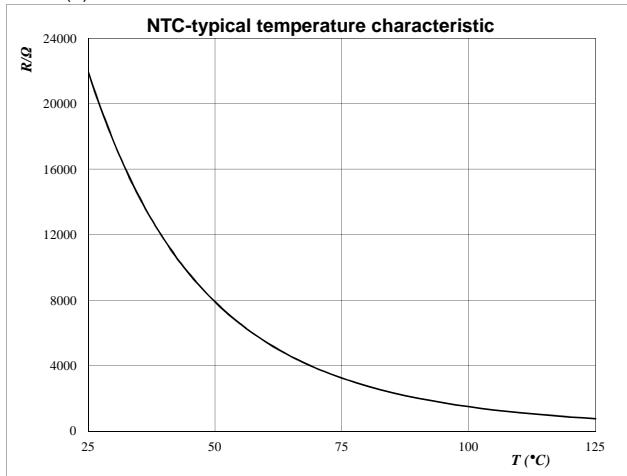
## Thermistor

**Figure 1**

Thermistor

Typical NTC characteristic  
as a function of temperature

$$R_T = f(T)$$



## Switching Definitions H-Bridge IGBT

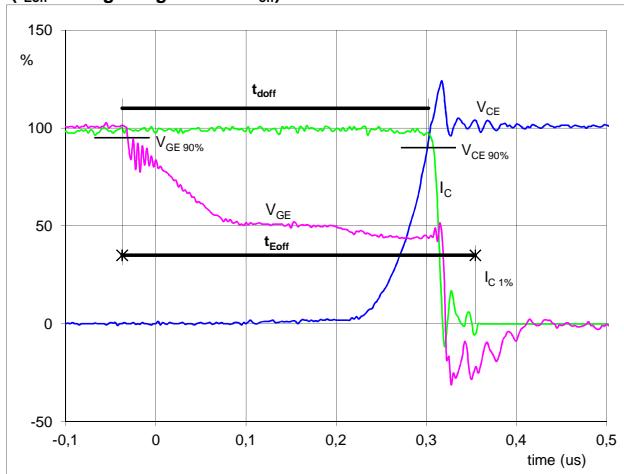
General conditions

$T_j$	=	125 °C
$R_{gon}$	=	8 Ω
$R_{goff}$	=	8 Ω

Figure 1

H-Bridge IGBT

Turn-off Switching Waveforms & definition of  $t_{doff}$ ,  $t_{Eoff}$   
( $t_{Eoff}$  = integrating time for  $E_{off}$ )

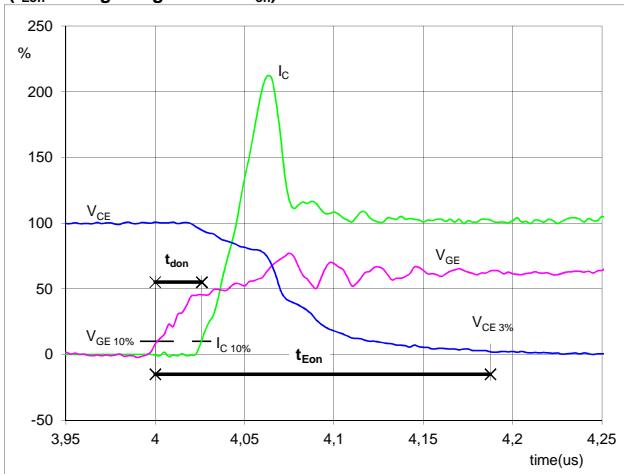


$V_{GE}(0\%) = 0 \text{ V}$   
 $V_{GE}(100\%) = 15 \text{ V}$   
 $V_C(100\%) = 400 \text{ V}$   
 $I_C(100\%) = 50 \text{ A}$   
 $t_{doff} = 0,33 \mu\text{s}$   
 $t_{Eoff} = 0,39 \mu\text{s}$

Figure 2

H-Bridge IGBT

Turn-on Switching Waveforms & definition of  $t_{don}$ ,  $t_{Eon}$   
( $t_{Eon}$  = integrating time for  $E_{on}$ )

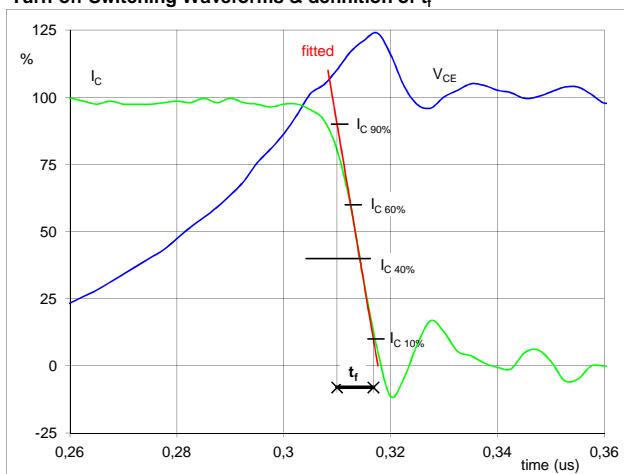


$V_{GE}(0\%) = 0 \text{ V}$   
 $V_{GE}(100\%) = 15 \text{ V}$   
 $V_C(100\%) = 400 \text{ V}$   
 $I_C(100\%) = 50 \text{ A}$   
 $t_{don} = 0,03 \mu\text{s}$   
 $t_{Eon} = 0,19 \mu\text{s}$

Figure 3

H-Bridge IGBT

Turn-off Switching Waveforms & definition of  $t_f$

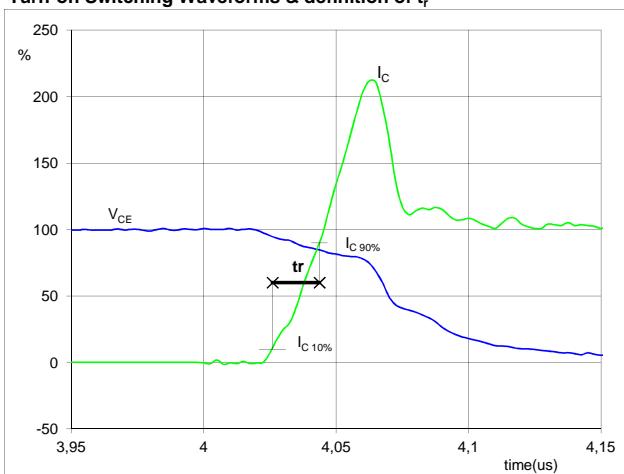


$V_C(100\%) = 400 \text{ V}$   
 $I_C(100\%) = 50 \text{ A}$   
 $t_f = 0,01 \mu\text{s}$

Figure 4

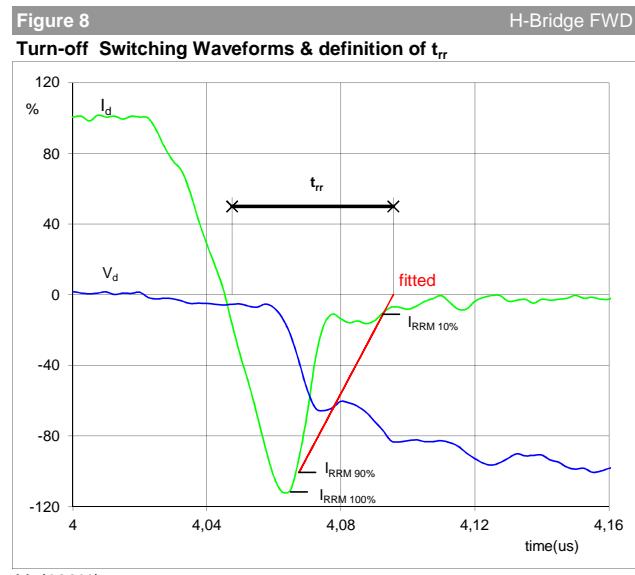
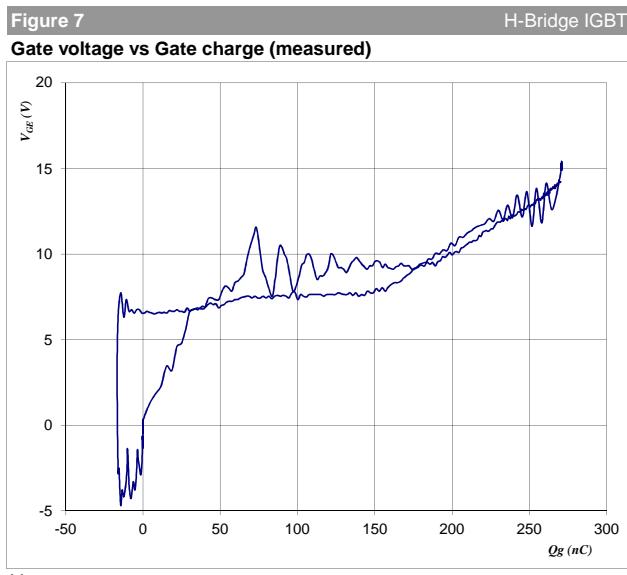
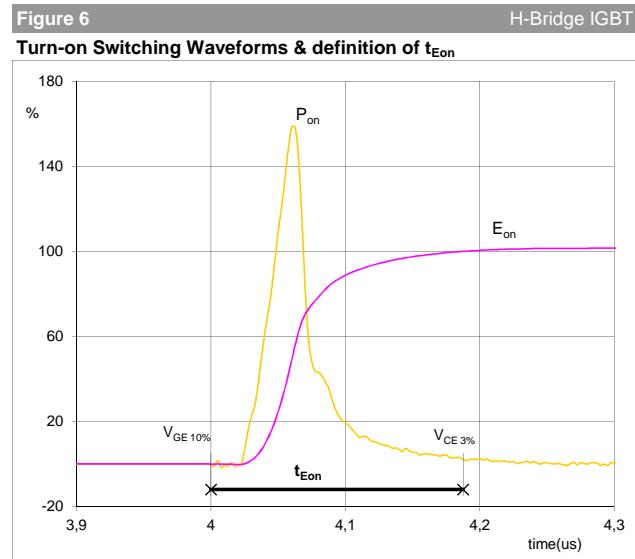
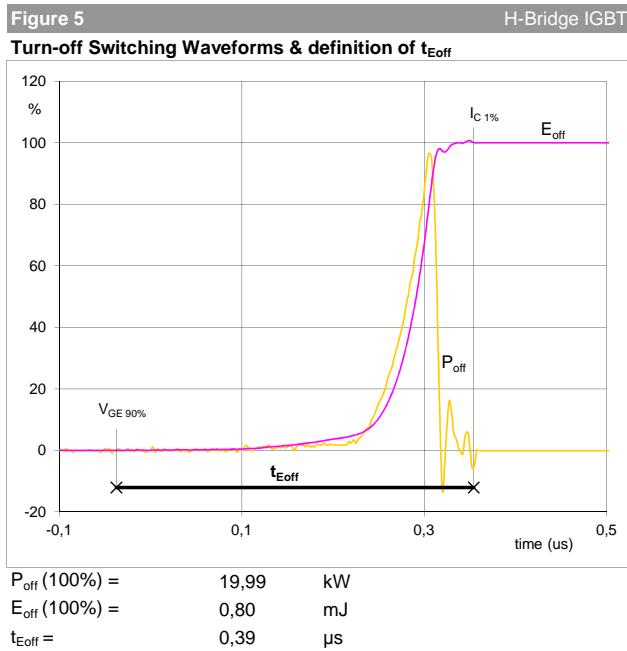
H-Bridge IGBT

Turn-on Switching Waveforms & definition of  $t_r$



$V_C(100\%) = 400 \text{ V}$   
 $I_C(100\%) = 50 \text{ A}$   
 $t_r = 0,02 \mu\text{s}$

## Switching Definitions H-Bridge IGBT

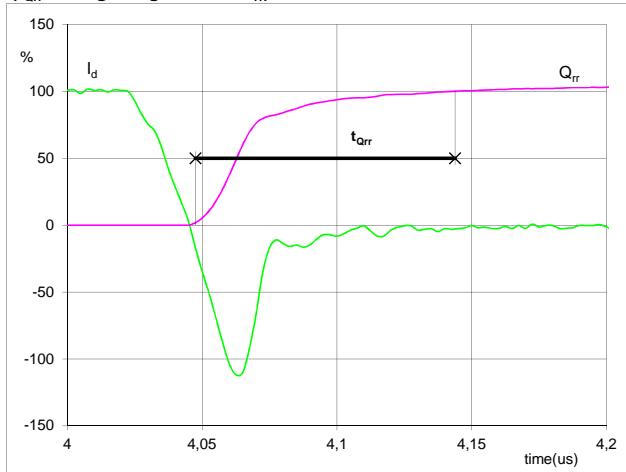


## Switching Definitions H-Bridge IGBT

**Figure 9**

H-Bridge FWD

**Turn-on Switching Waveforms & definition of  $t_{Qrr}$**   
( $t_{Qrr}$  = integrating time for  $Q_{rr}$ )

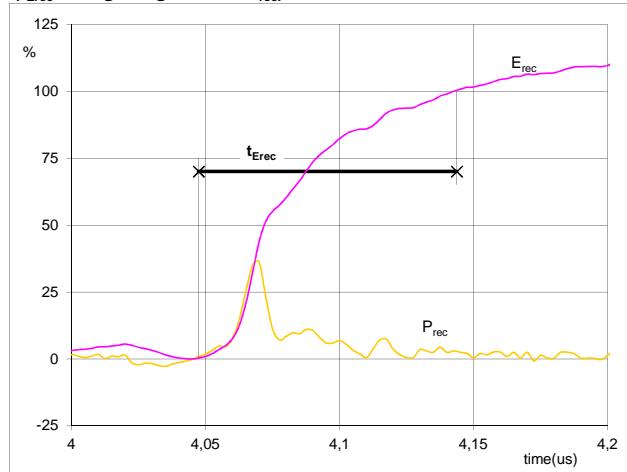


$I_d(100\%) = 50 \text{ A}$   
 $Q_{rr}(100\%) = 1,16 \mu\text{C}$   
 $t_{Qrr} = 0,10 \mu\text{s}$

**Figure 10**

H-Bridge FWD

**Turn-on Switching Waveforms & definition of  $t_{Erec}$**   
( $t_{Erec}$  = integrating time for  $E_{rec}$ )



$P_{rec}(100\%) = 19,99 \text{ kW}$   
 $E_{rec}(100\%) = 0,13 \text{ mJ}$   
 $t_{Erec} = 0,10 \mu\text{s}$

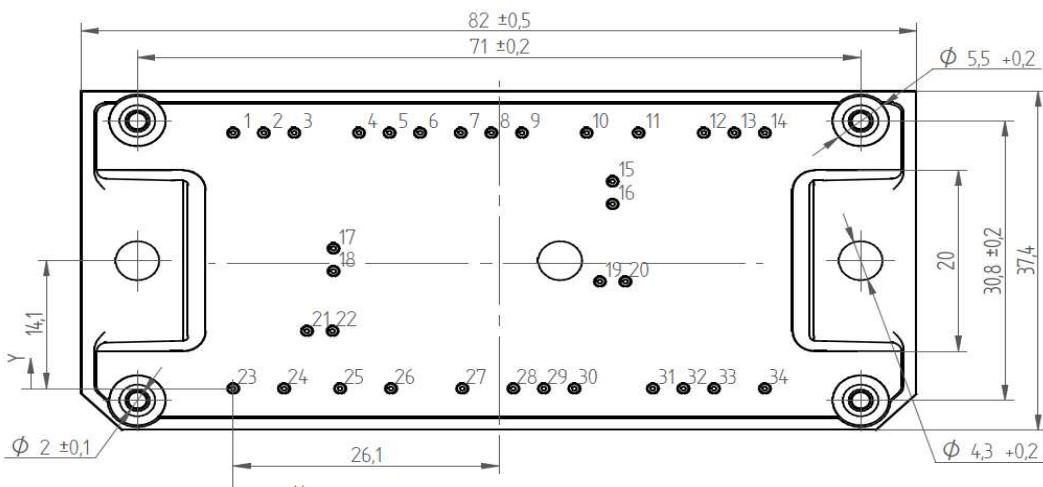
## Ordering Code and Marking - Outline - Pinout

### Ordering Code & Marking

Version	Ordering Code	in DataMatrix as	in packaging barcode as
without thermal paste 12mm housing	10-FY06BIA050SG-M523E18	M523E18	M523E18

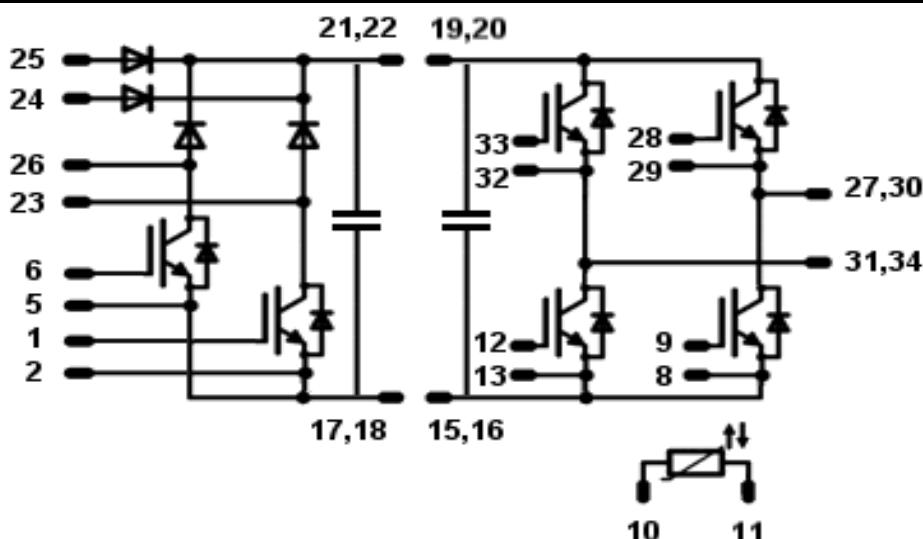
### Outline

Pin table		
Pin	X	Y
1	0	28,2
2	3	28,2
3	6	28,2
4	12,35	28,2
5	15,35	28,2
6	18,35	28,2
7	22,35	28,2
8	25,35	28,2
9	28,35	28,2
10	34,7	28,2
11	39,8	28,2
12	46,2	28,2
13	49,2	28,2
14	52,2	28,2
15	37,25	22,85
16	37,25	20,35
17	9,85	15,45
18	9,85	12,95
19	36	11,8
20	38,5	11,8
21	7,25	6,35
22	9,75	6,35
23	0	0
24	5	0
25	10,5	0
26	15,5	0
Pin table		
27	22,5	0
28	27,5	0
29	30,5	0
30	33,5	0
34	52,2	0



Tolerance of pinpositions: ±0,5mm at the end of pins  
 Dimension of coordinate axis is only offset without tolerance  
 PCB cutouts and holes see in handling instructions document

### Pinout



Pins 3,4,7,14 are not connected.

Pins 27 and 30 have to be connected together

Pins 31 and 34 have to be connected together

**PRODUCT STATUS DEFINITIONS**

Datasheet Status	Product Status	Definition
Target	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice. The data contained is exclusively intended for technically trained staff.
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2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.